

**HORIBA**  
Explore the future

**Jeff Bodycomb, Ph.D.**

# Sieving Without Sieves

**March 15<sup>th</sup> 2016**



# Topics

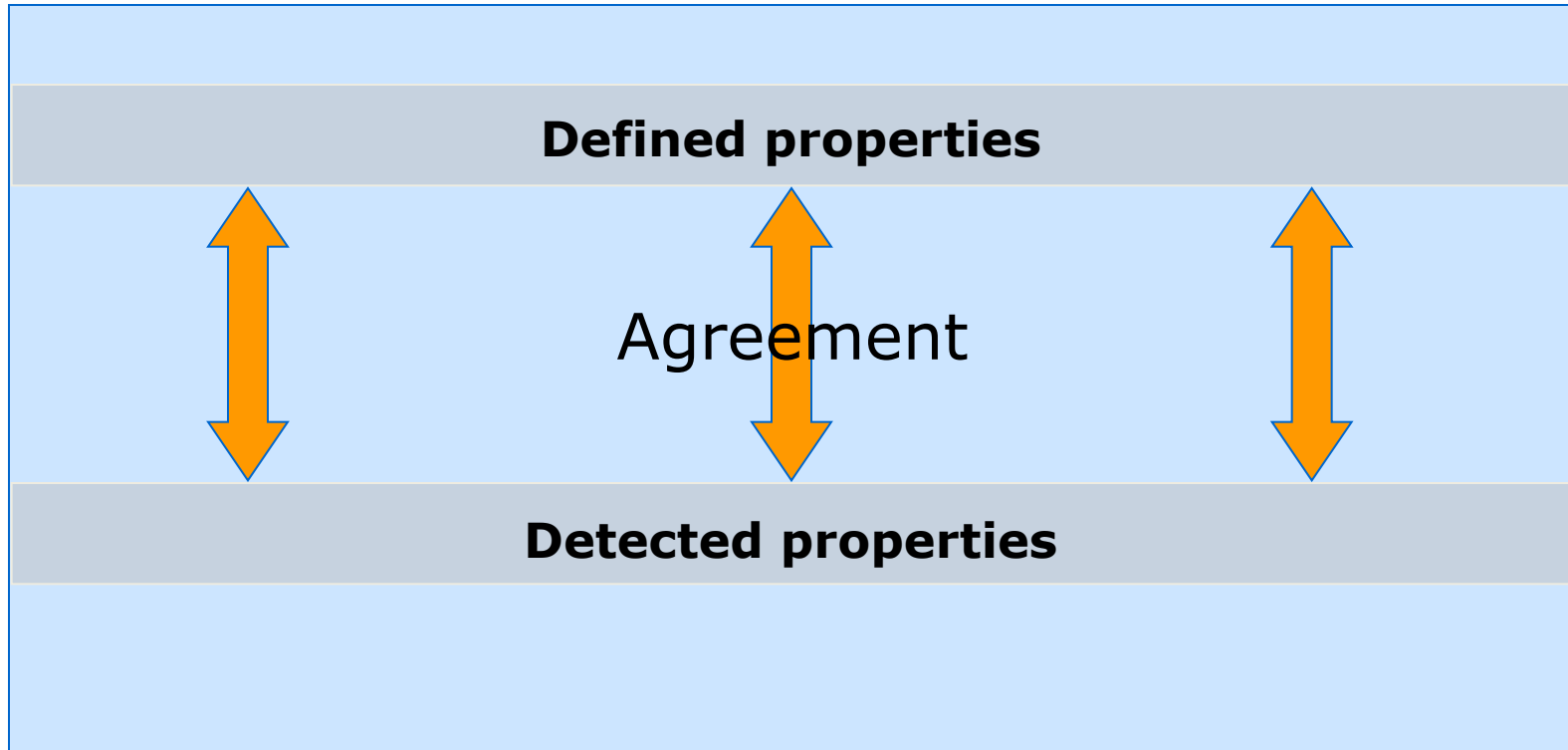
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**Particle analysis**

**Sieving**

**Sieve replacement with  
image analysis and the CAMSIZER**

# Motivation for particle sizing



Certain properties are to be achieved when **products** are manufactured.  
These depend on the **particle size** and the **particle distribution**.

➡ **Particle size/distribution = product property**

# Motivation for particle sizing

## Example 1: Coffee

The particle size determines important taste properties

**Too coarsely** ground coffee: a watery cup of coffee

**Too finely** ground coffee: too many aromatics, acids and bittering agents are dissolved, the filter could be blocked or fines arrive in the coffee cup



# Motivation for particle sizing

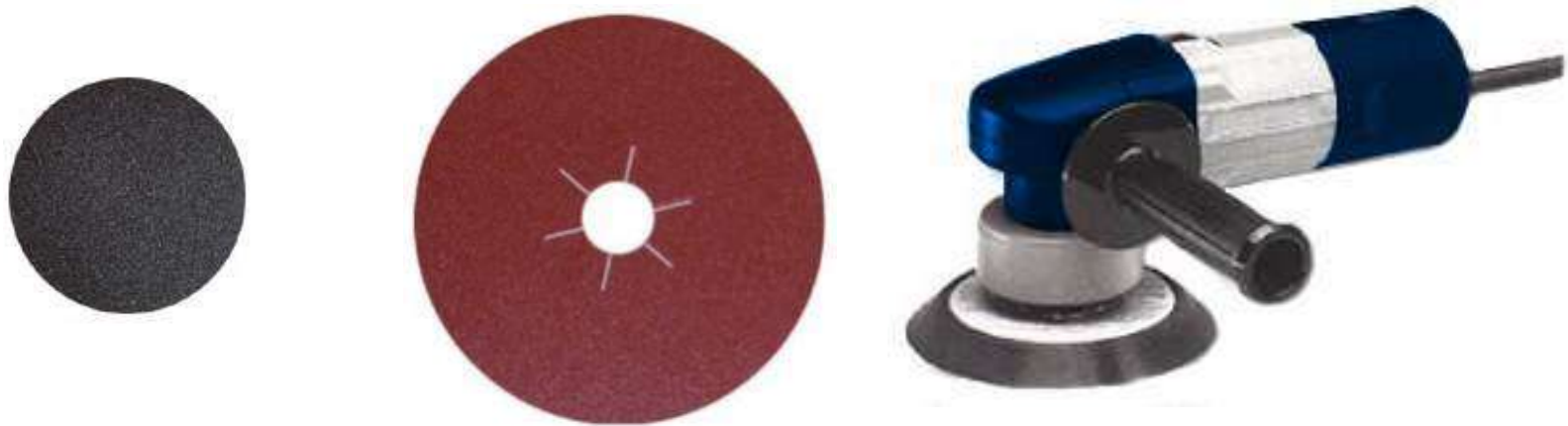
## Example 2: Sandpaper

The quality of the sanding result is always determined by the particle size distribution of the abrasive.

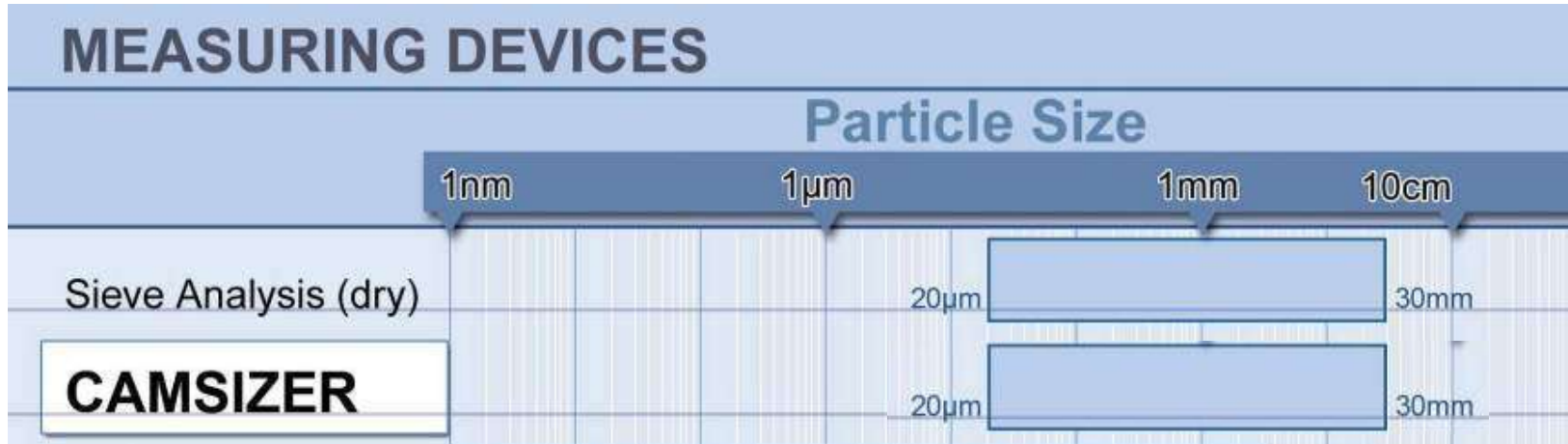
**Incorrect Size** wrong surface finish

**Too wide** particle size distribution:

Generates grooves and rills on the surface.



# Measuring systems





# Sieving

Traditional measurement:

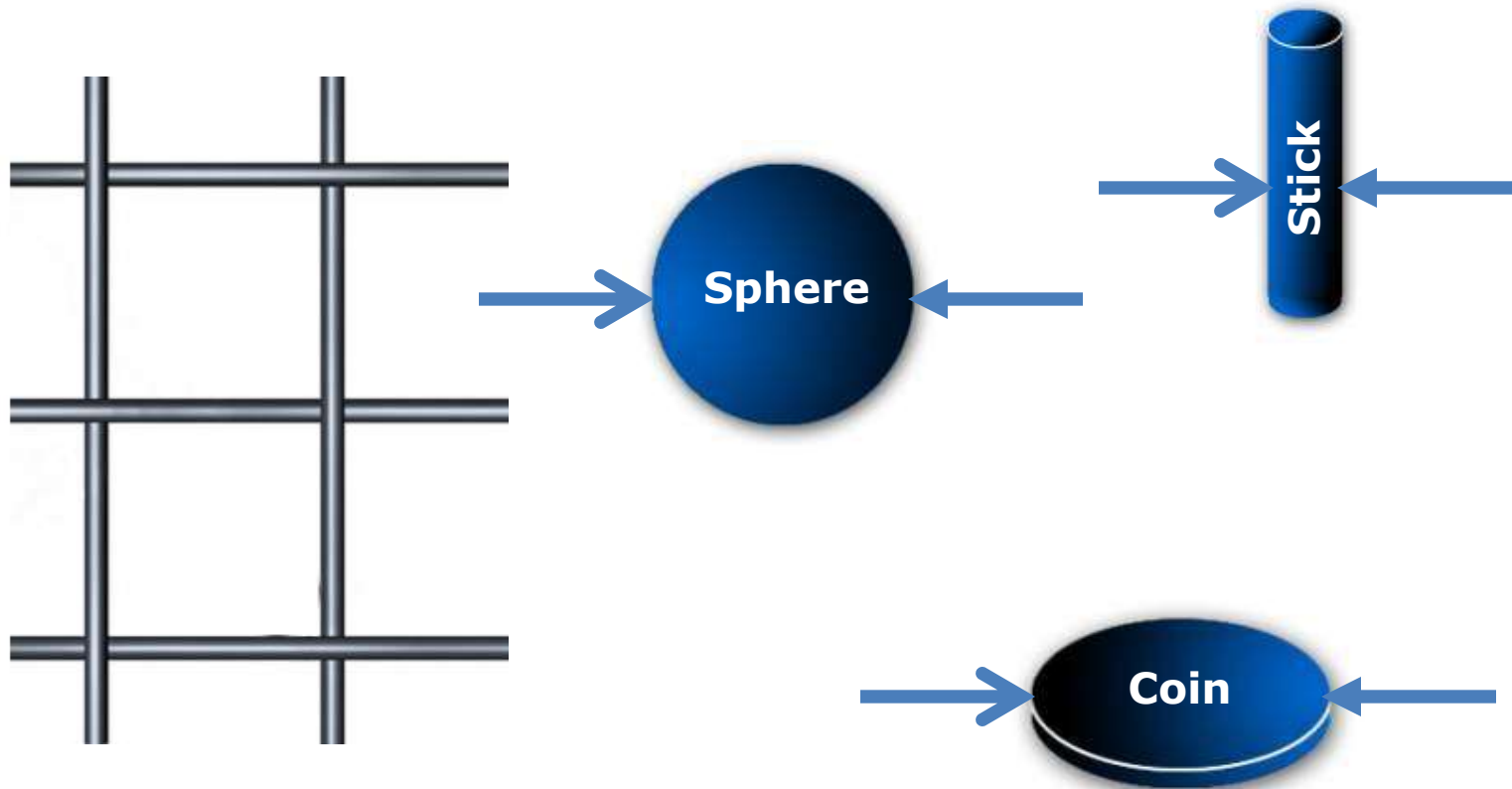
- Sieve analysis 0.02mm – 30mm
  - Sufficient statistics in a short time
- until now: older optical systems had poor statistics





# Measuring principle: sieving

**What size particle passes through a two dimensional (often square) hole?**

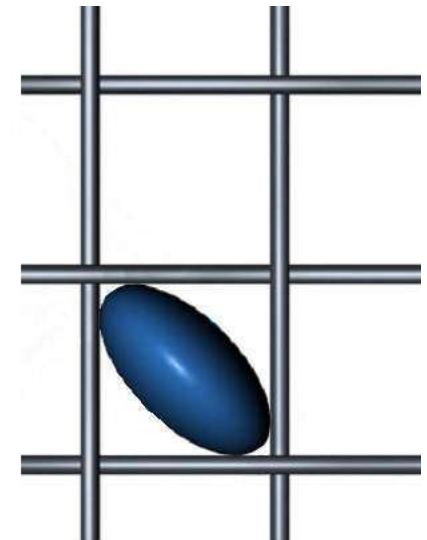
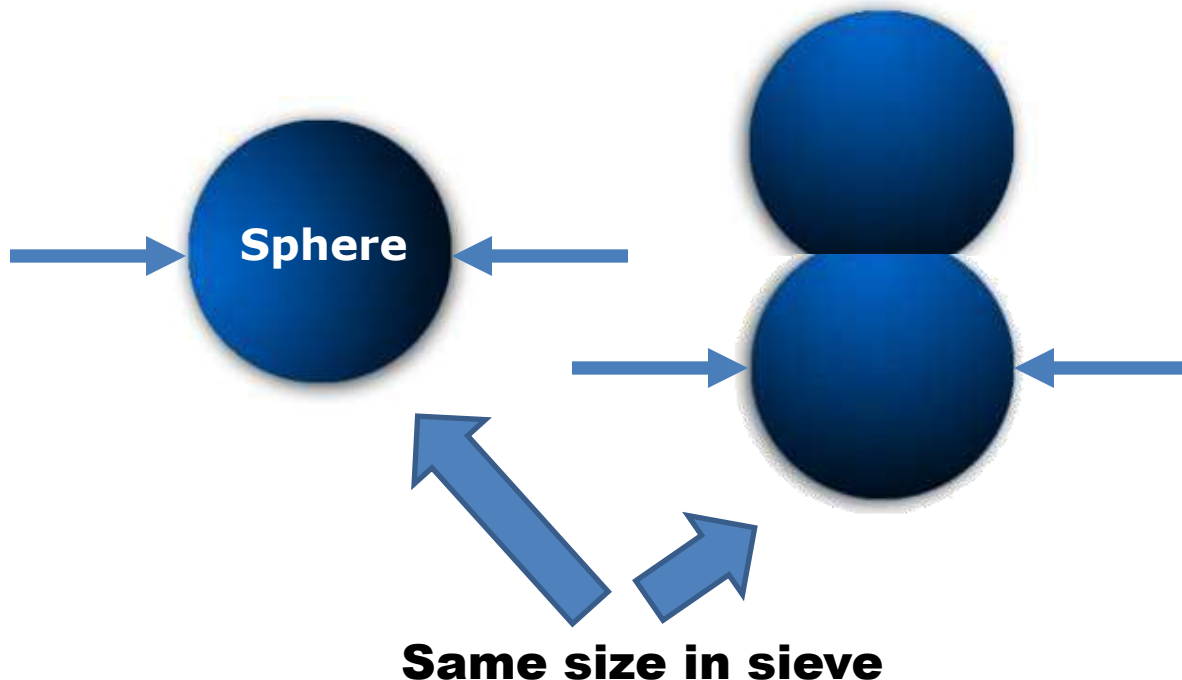


# Measuring principle: sieving

**What size particle passes through a two dimensional (often square) hole?**

**Surprises!**

**Doublet from Spray Drying**



**Lenticular particle (e.g., pill)... no simple dimension**

# Standards for sieving

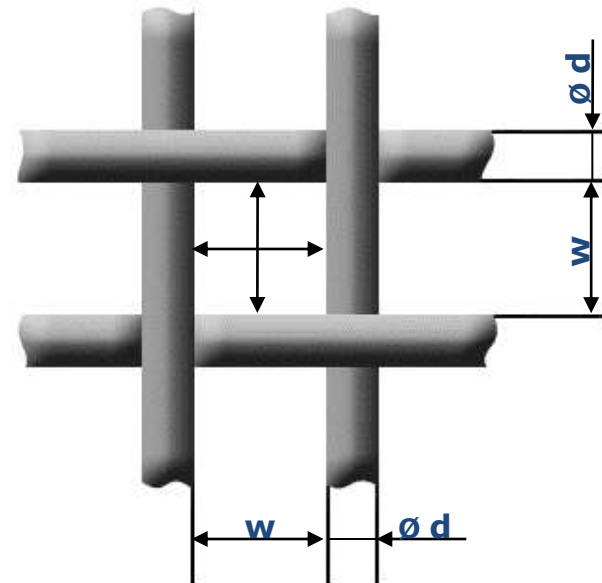


If sieve analysis is used for quality control within the context of DIN EN ISO 9000:2000 then both the **sieve shaker** and the **test sieves** must be subjected to test agent monitoring.

## Technical requirements & testing according to ISO 3310

### Tolerance for mean value ( $Y$ ):

The mean value of the mesh width must not differ from the nominal value  $w$  by more than the tolerance  $\pm Y$ .



$w$  = mesh width  
 $d$  = wire diameter

# Sieve analysis: workflow



# Measurement

**Add known mass of sample to top of sieve stack.**

**Shake and allow smaller particles to pass through stack.**

**Remove each screen and weigh particle fractions on screen.**

**Analyze Data.**

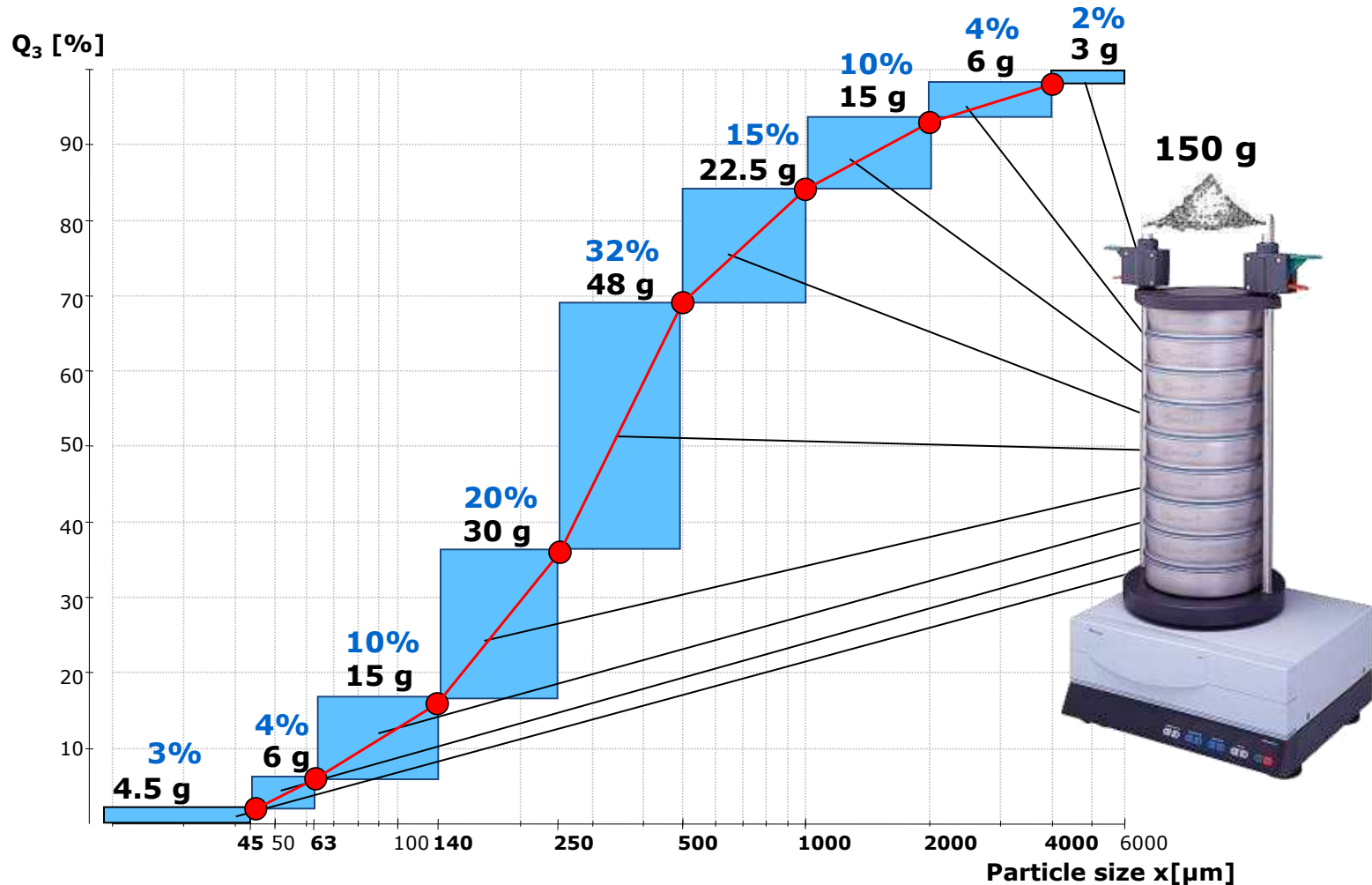


**Clean sieves for the next user.**



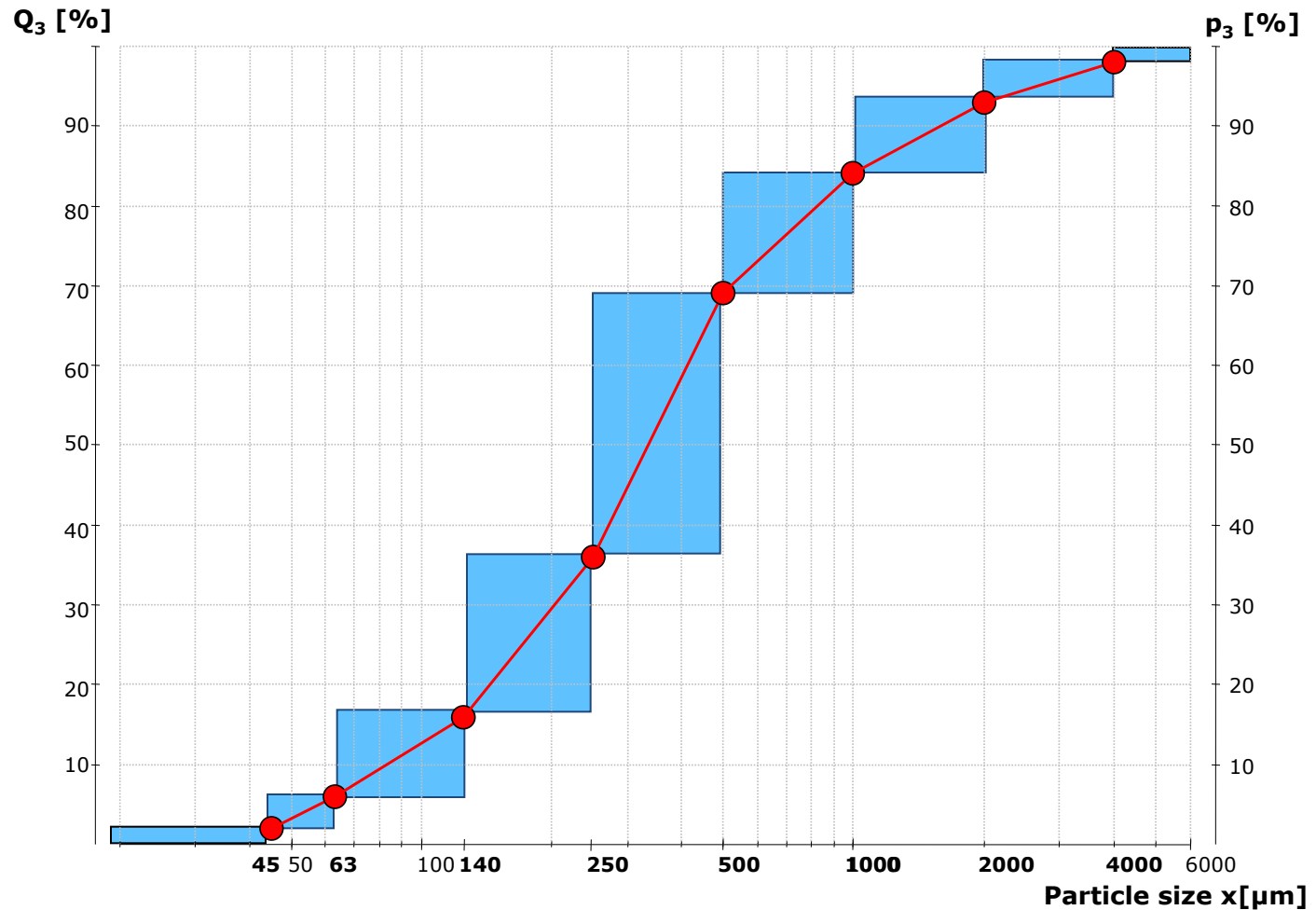
# Visualization

## Cumulative distribution



# Visualization

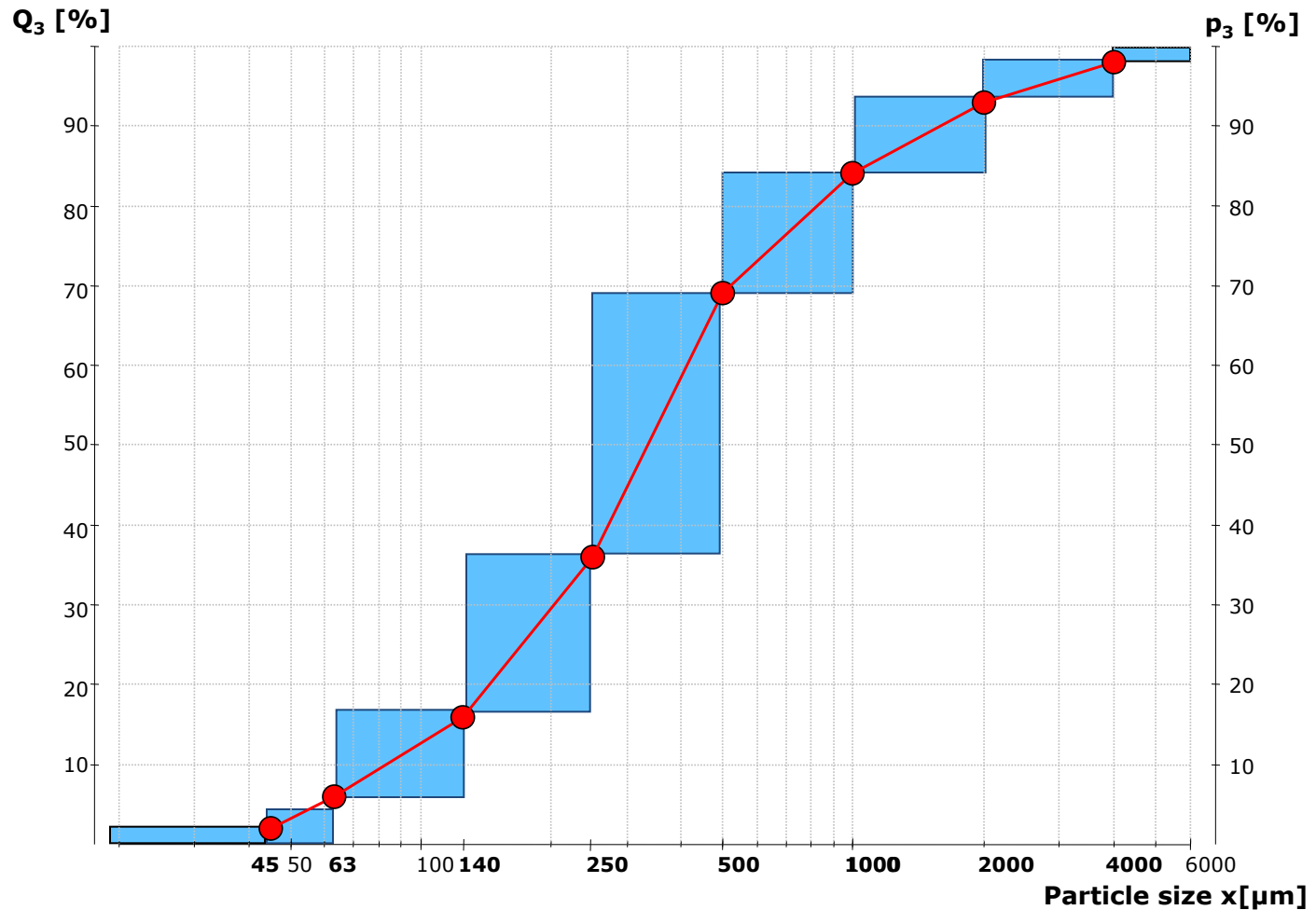
## Cumulative distribution





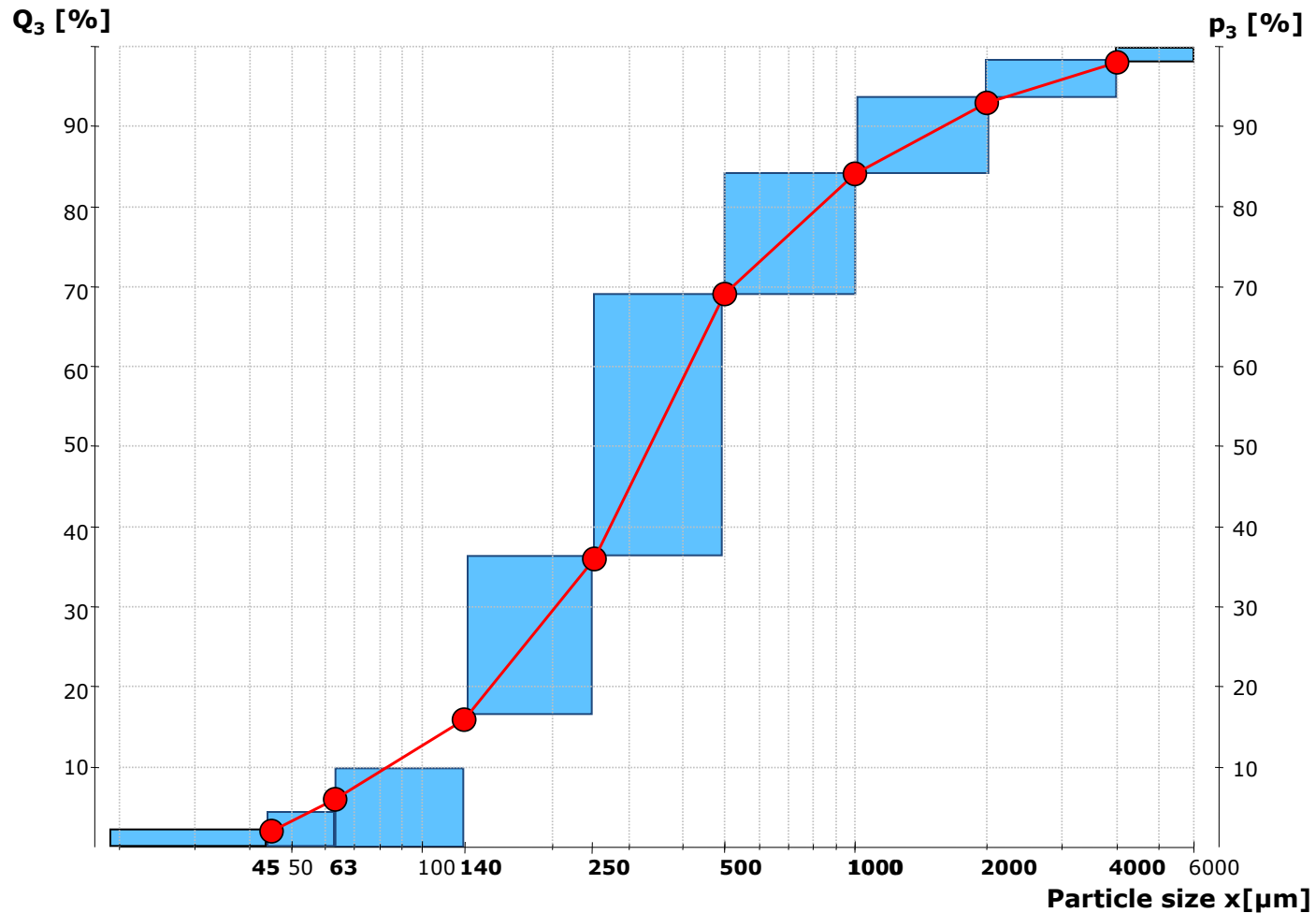
# Visualization

## Cumulative distribution



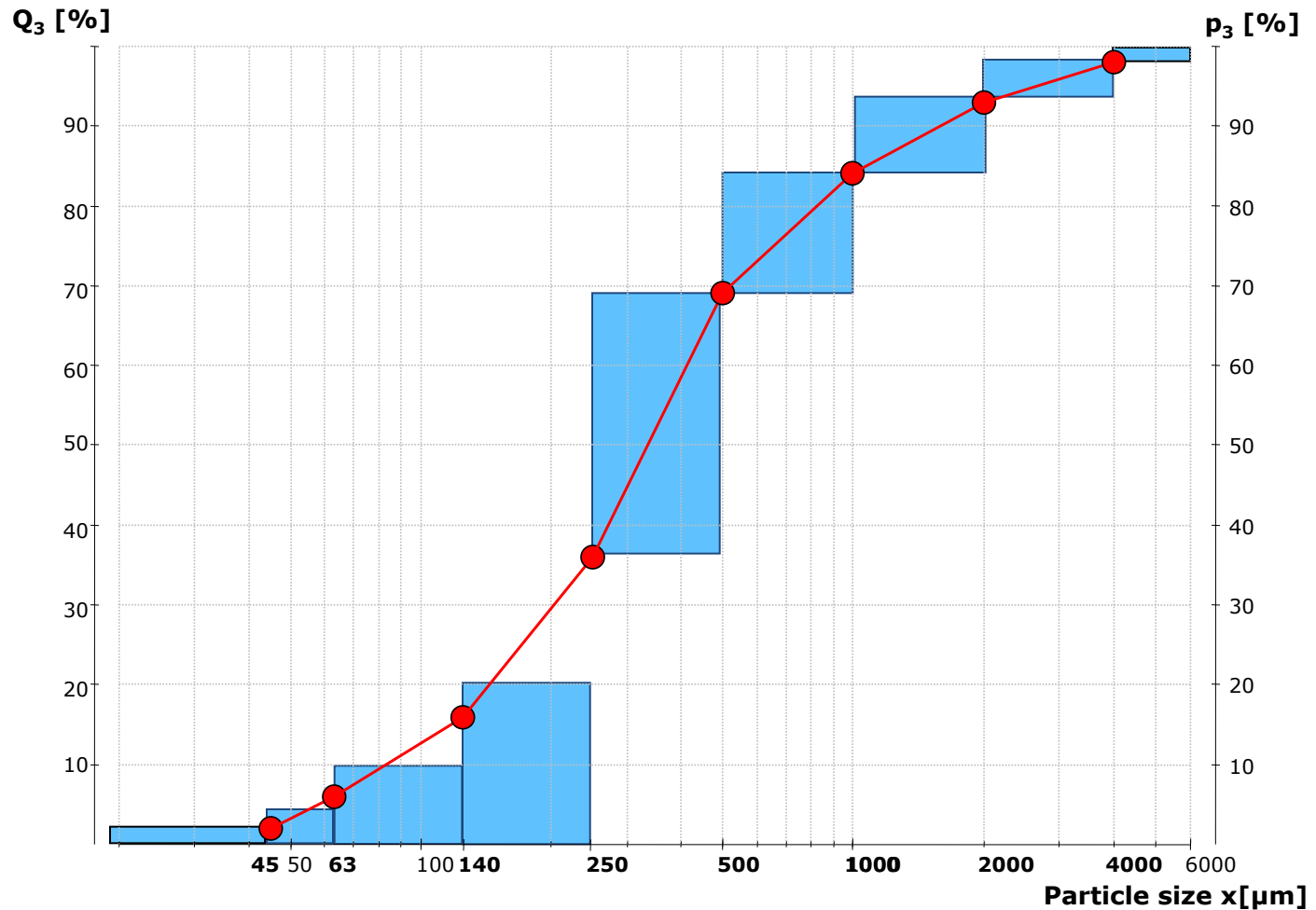
# Visualization

## Cumulative distribution



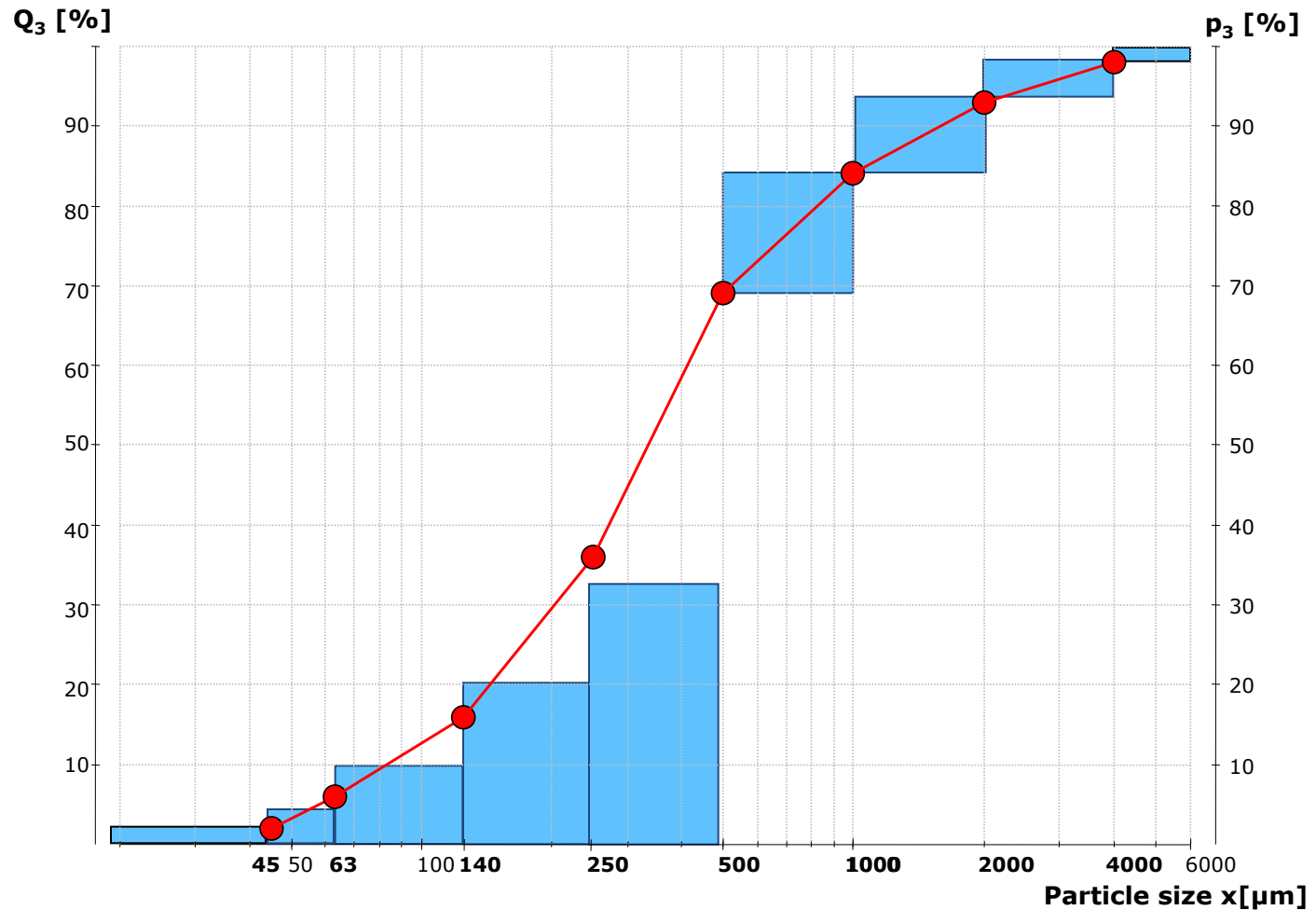
# Visualization

## Cumulative distribution



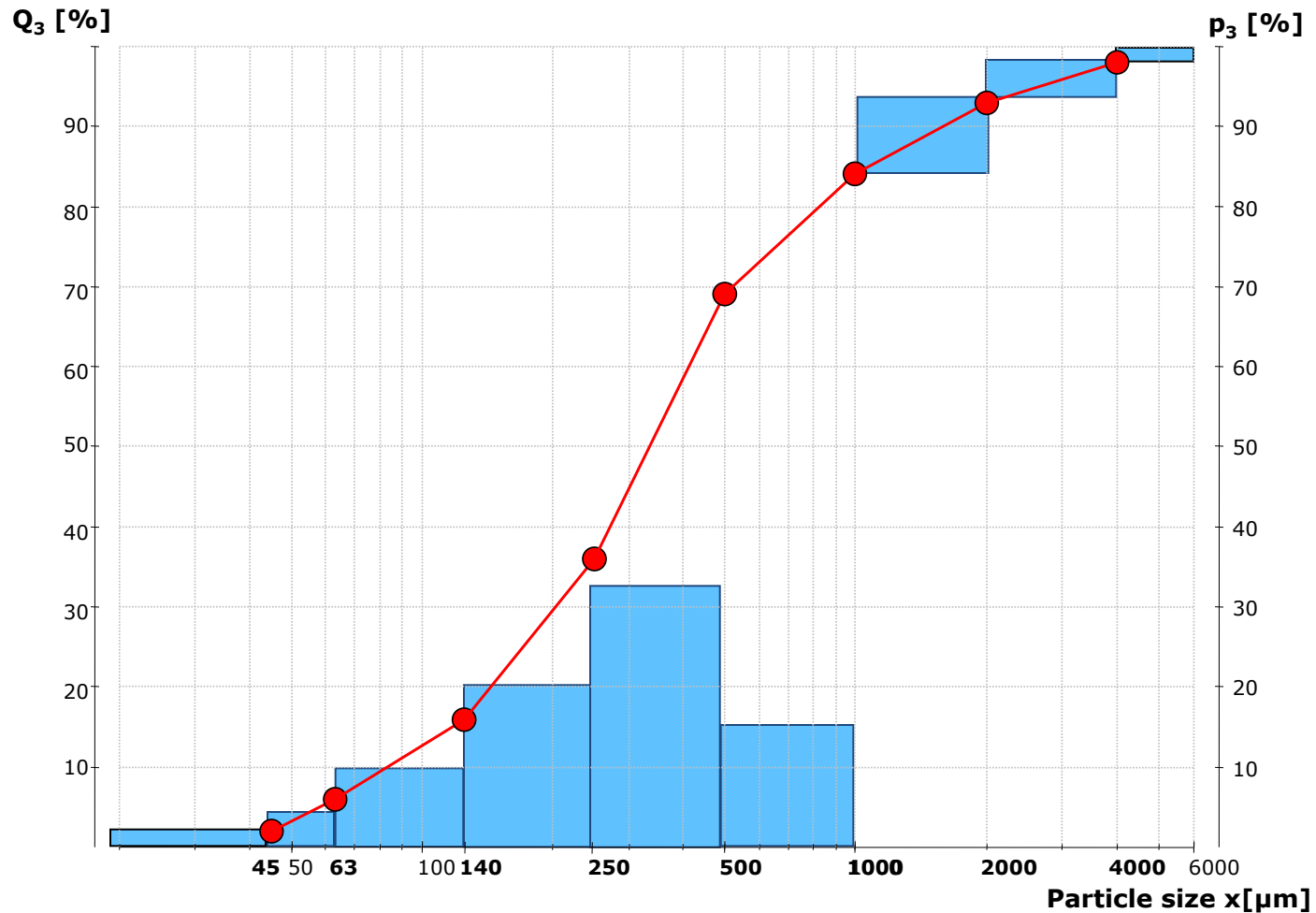
# Visualization

## Cumulative distribution



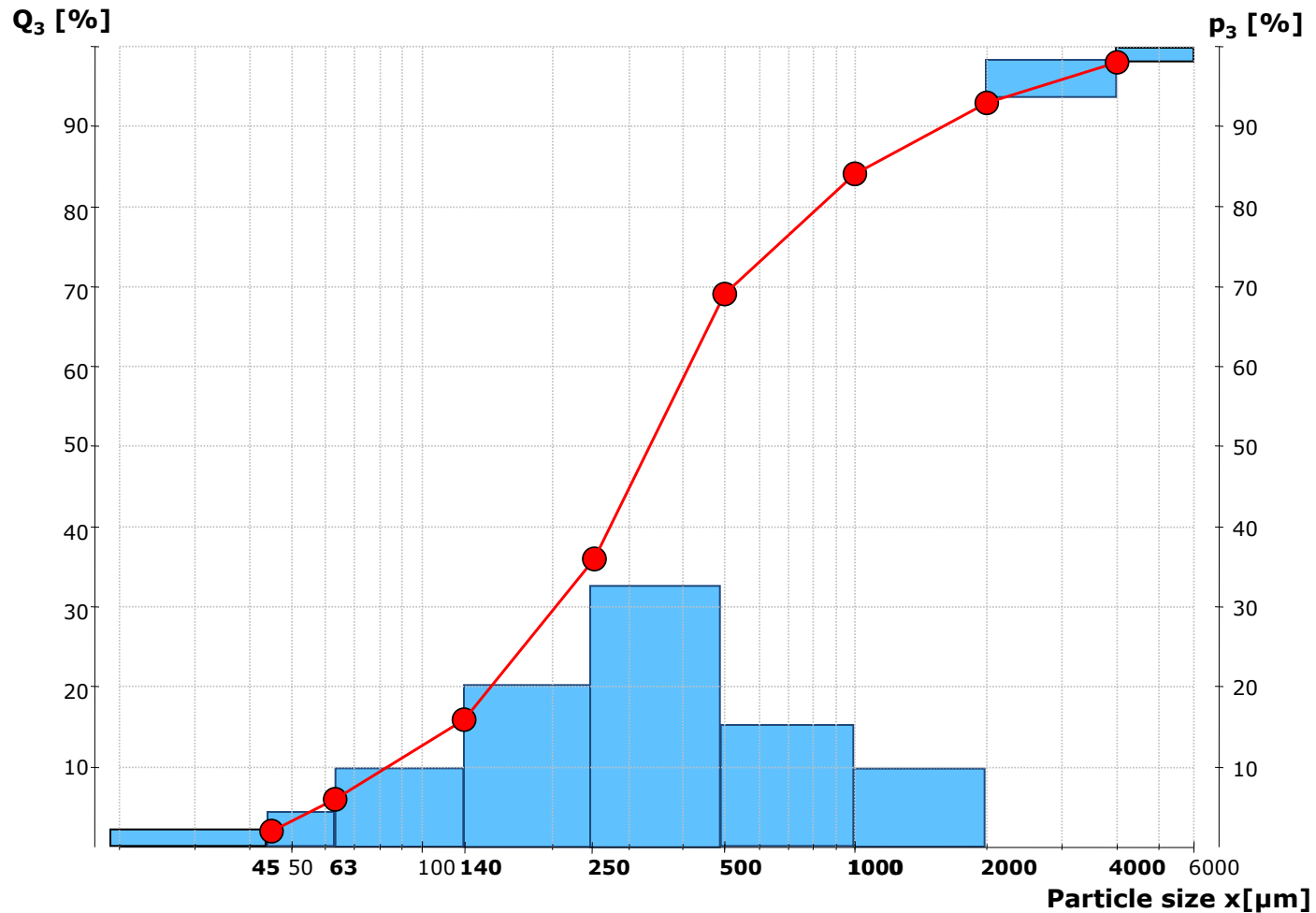
# Visualization

## Cumulative distribution



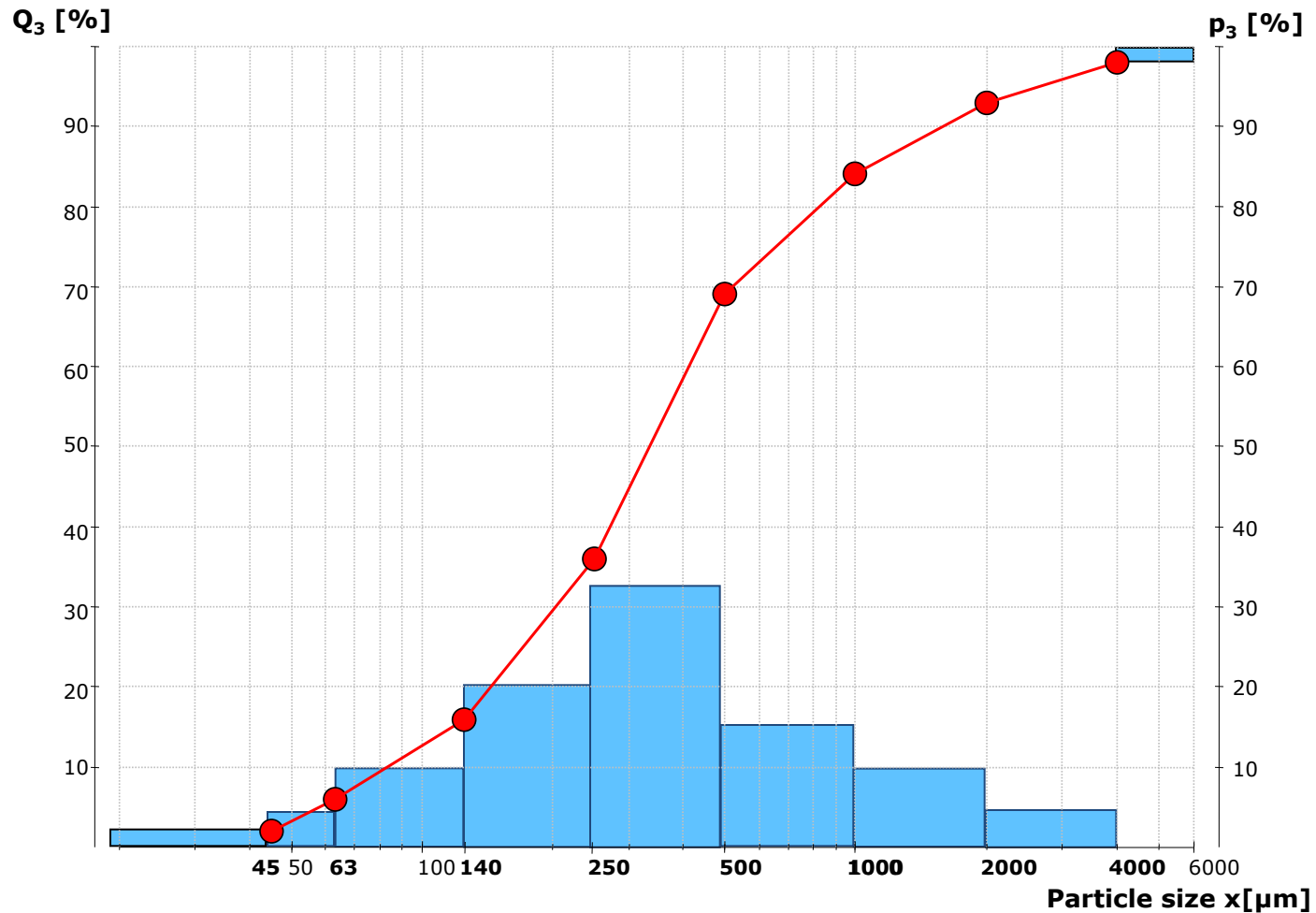
# Visualization

## Cumulative distribution



# Visualization

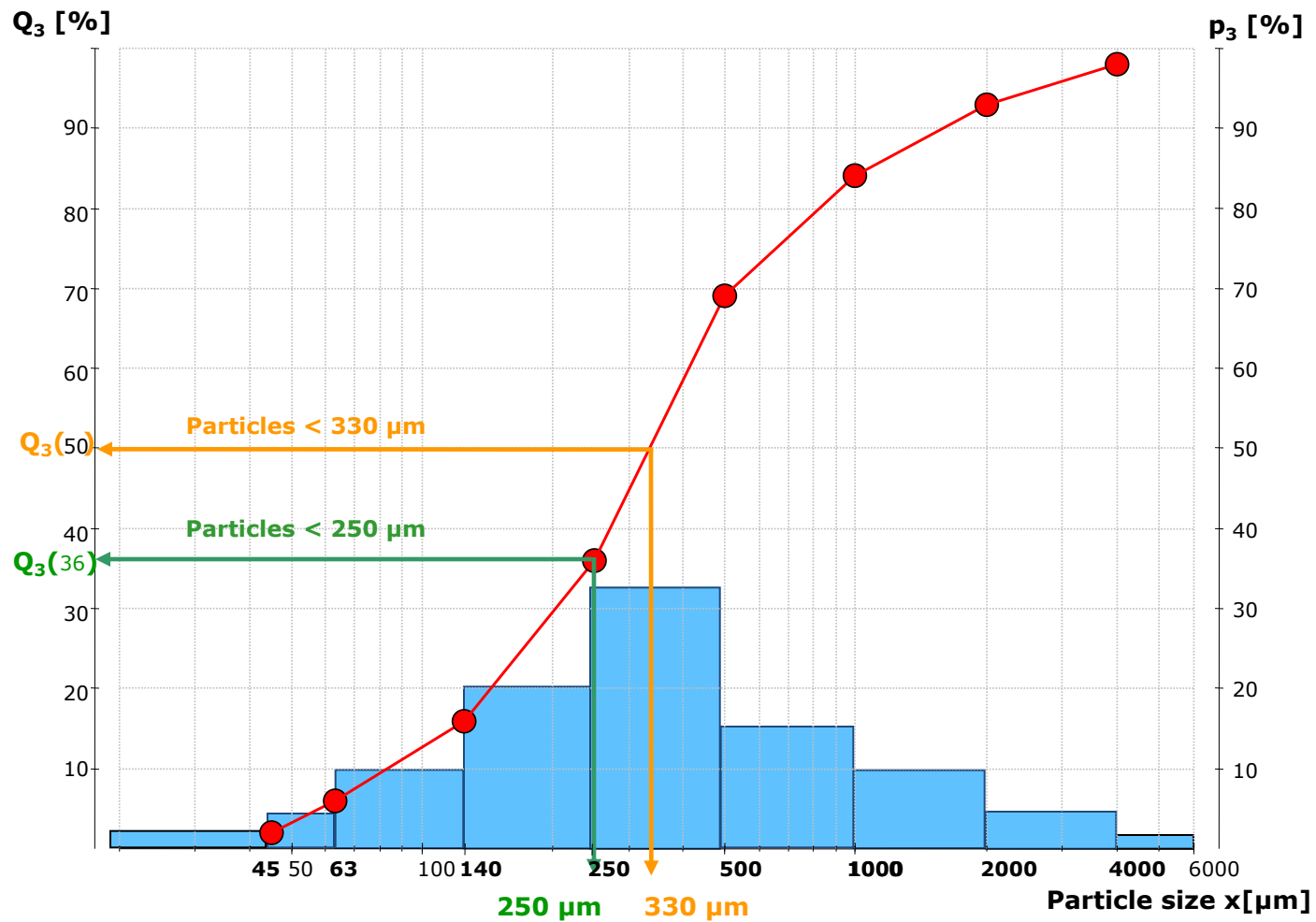
## Cumulative distribution



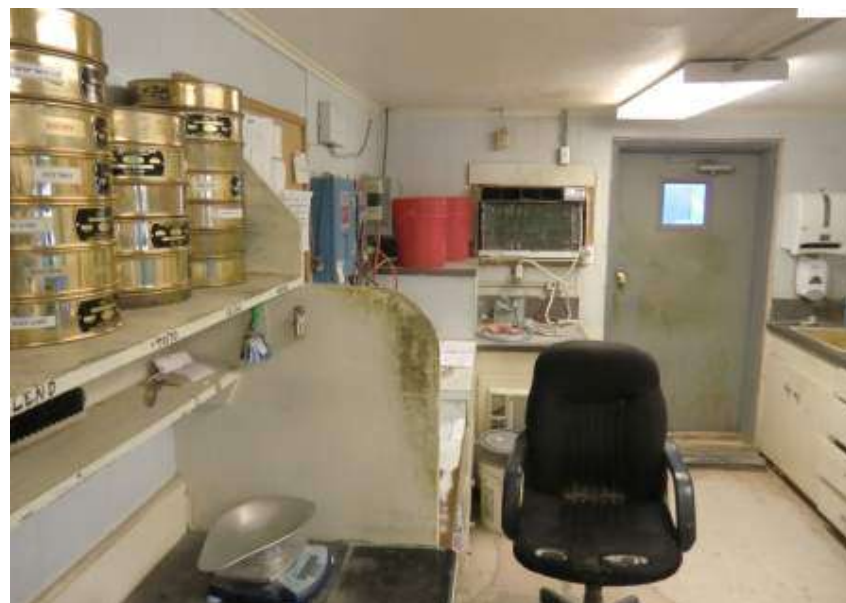


# Visualization

## Cumulative distribution



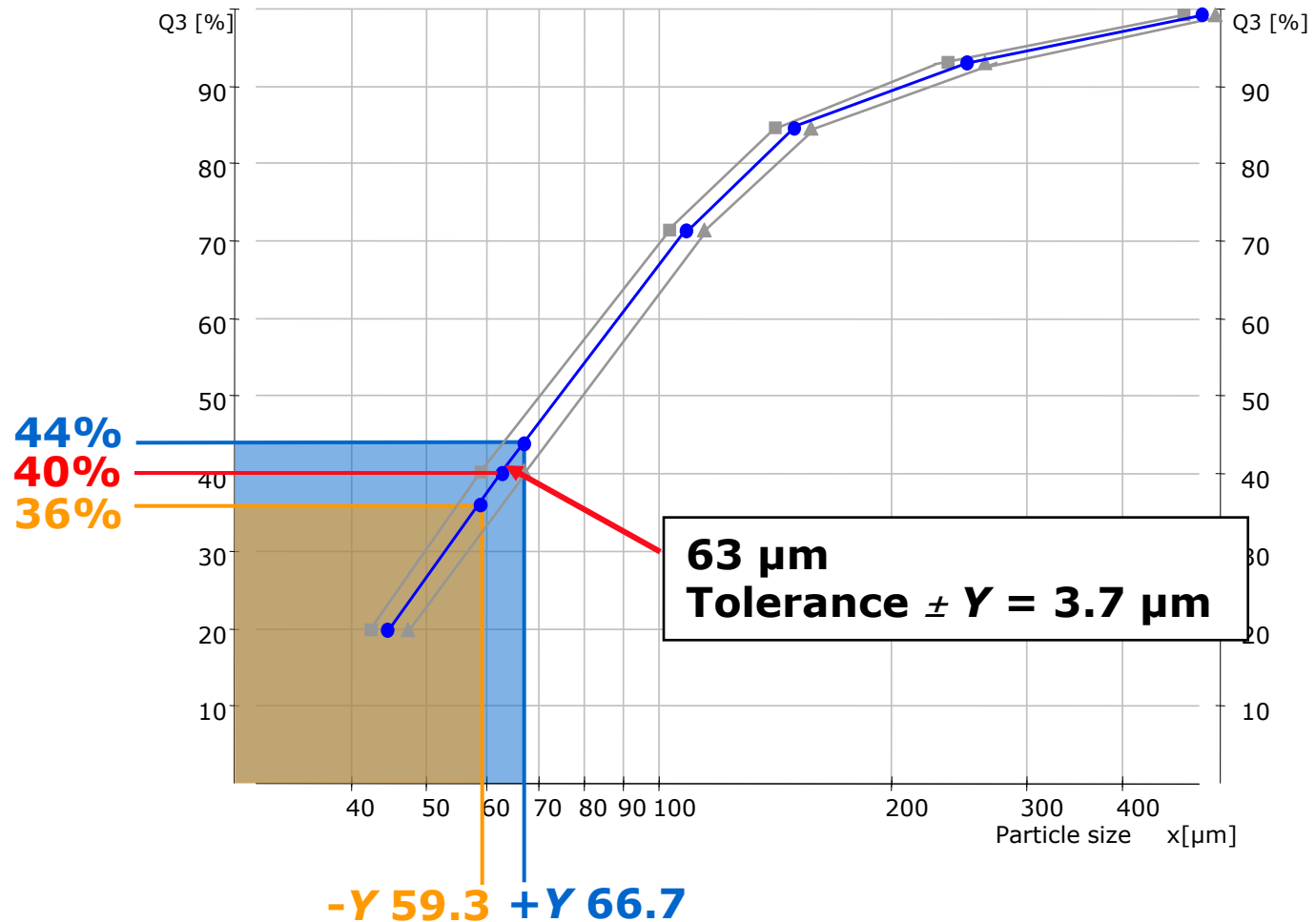
# Quality monitoring problems (size)



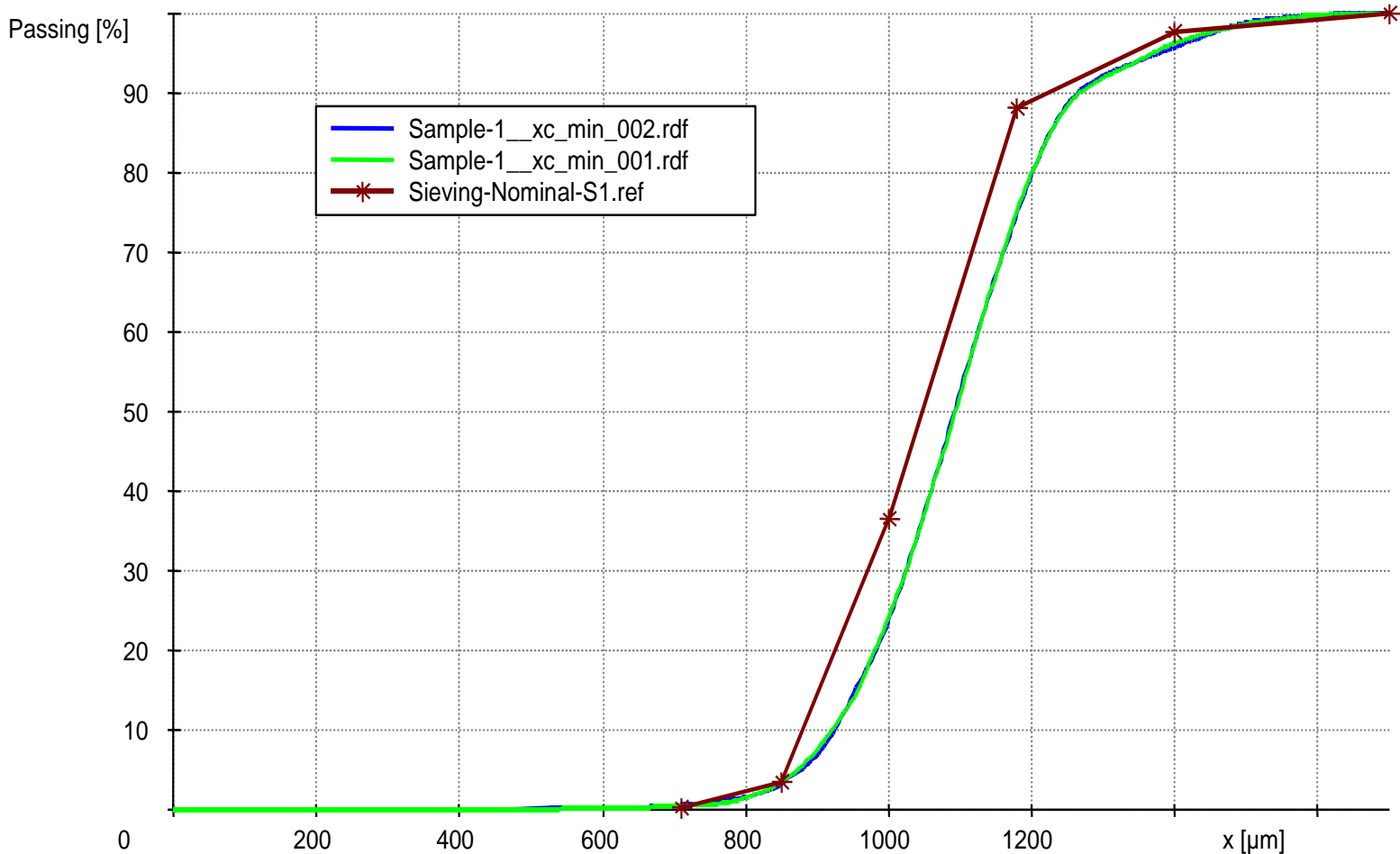
## Cross contamination and weighing problems

# Importance of mesh width

## consequences of tolerances



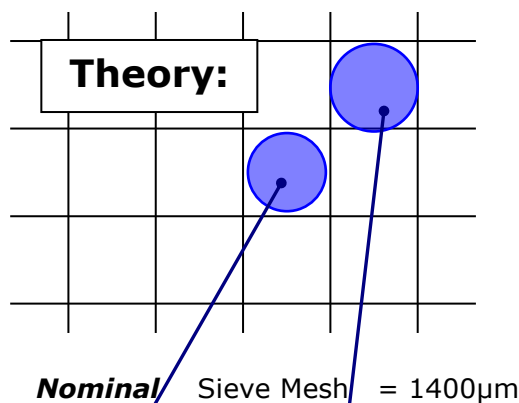
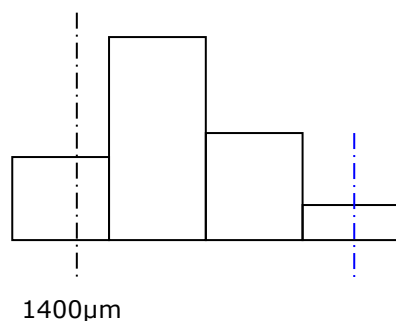
# Spherical particles



**In theory these curves should match. Why don't they?  
Hint: Look at the detailed sieve specification!**

# Influence of mesh width

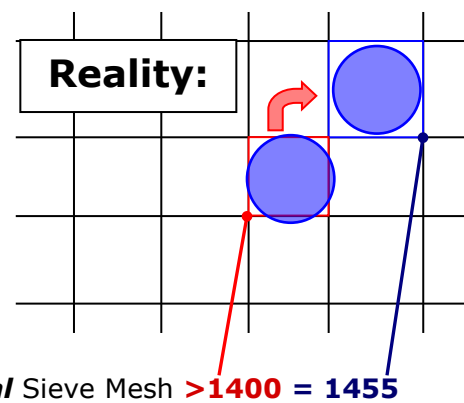
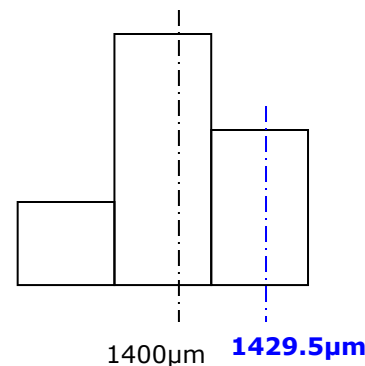
**Mesh sizes warp**



only beads < 1400µm  
will **pass** the sieve mesh

beads > 1400µm will **not pass** the  
sieve mesh

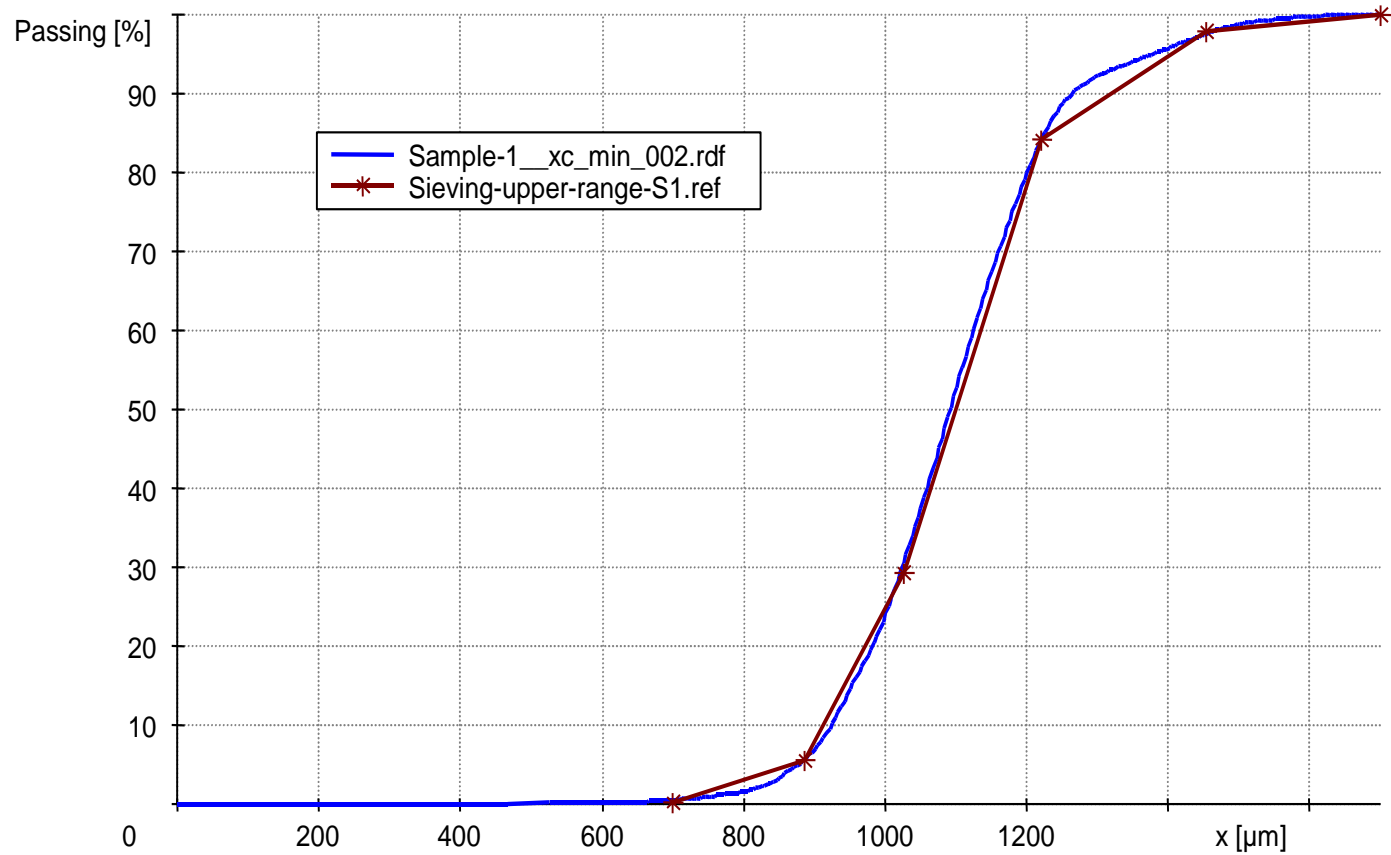
**Mesh sizes weft**



**Real Sieve Mesh** > 1400 = 1455

Upper mesh size range ~1455µm  
sieve No. 03033531 (nominal 1400µm)

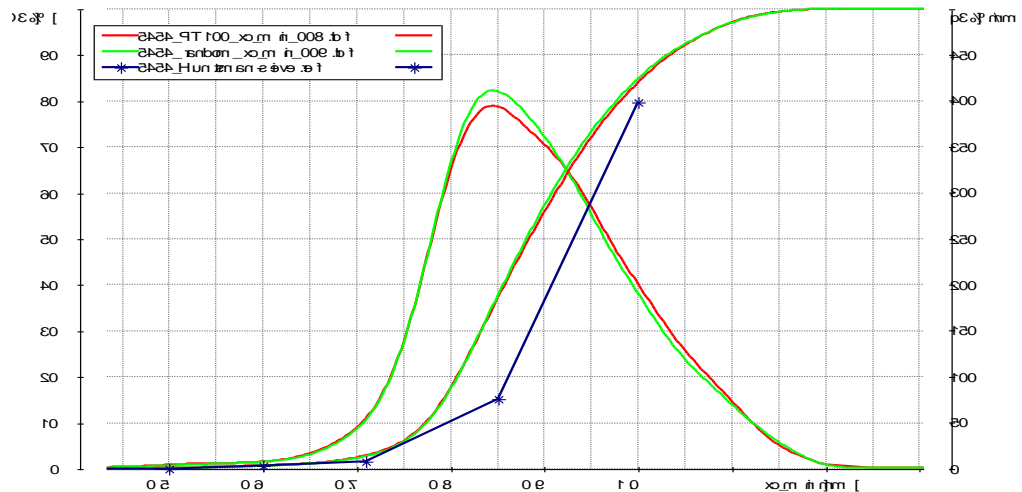
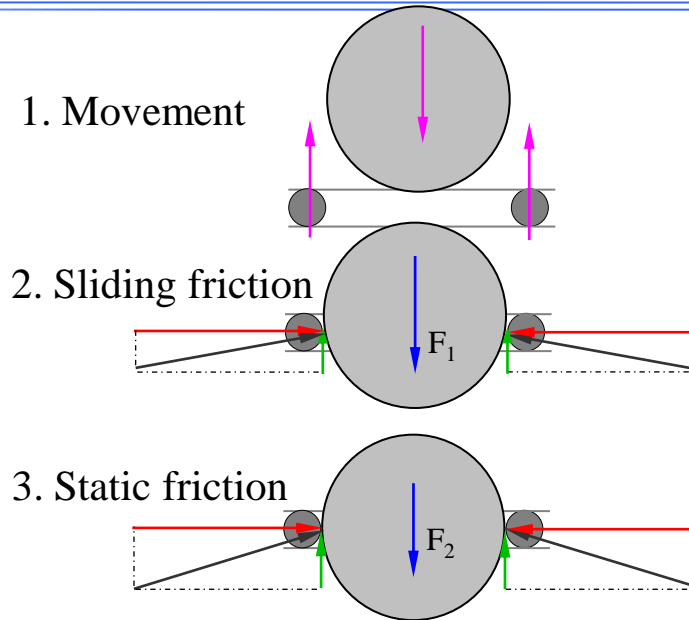
# Real mesh width





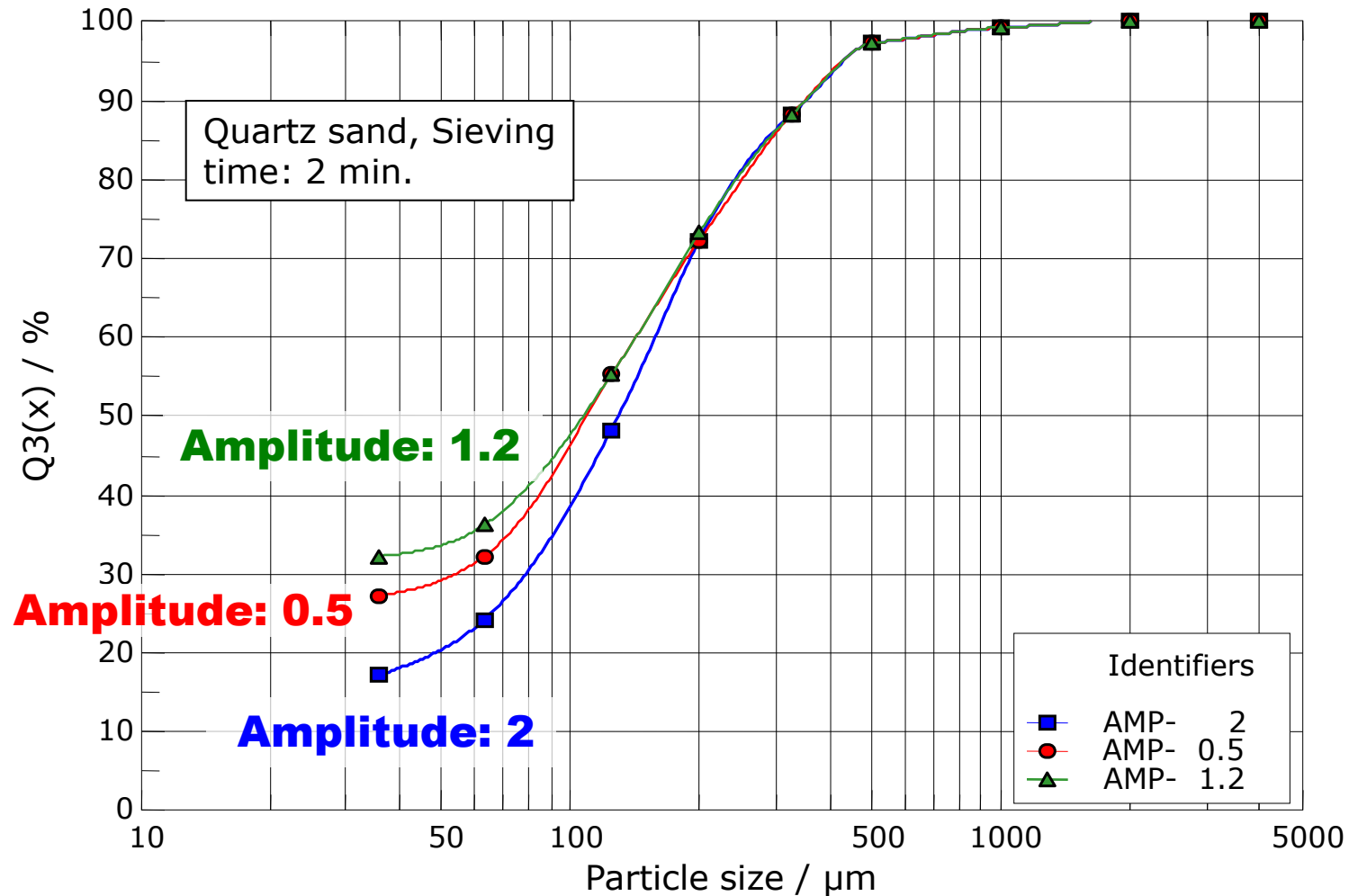
# Particles get stuck in sieves

**Round particles are easily captured but hardly released**





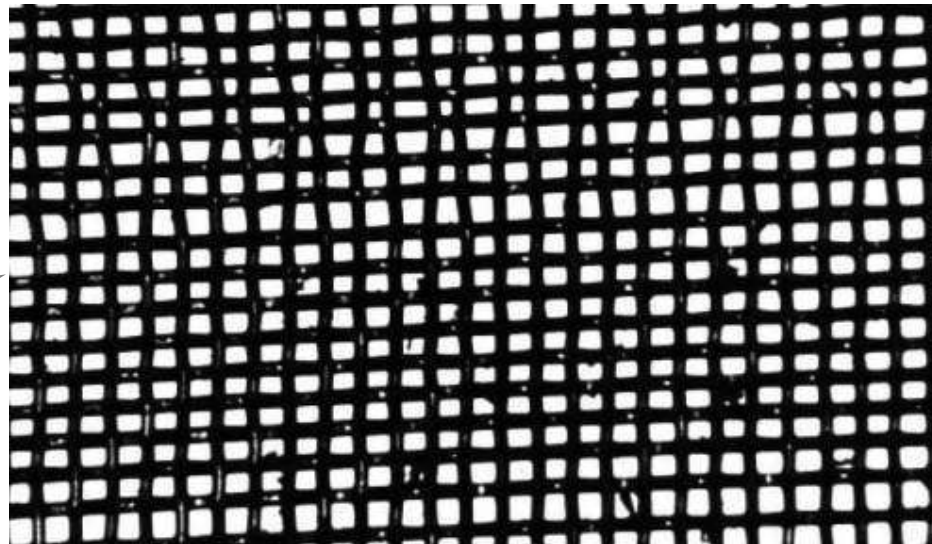
# Different shaking amplitude



# Watch out for wear!

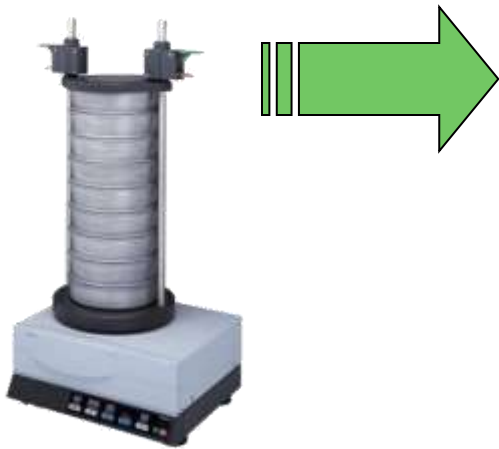
**“Beating” on sieves with particles (sieve analysis), or careless cleaning is going to wear out the sieves!**

**It requires a lot of work to monitor sieve condition.**



**Worn out sieves**

# Sieving advantages



- Robust and industrial-suited
- Easy handling
- Long history
- Low cost

# Sieving disadvantages



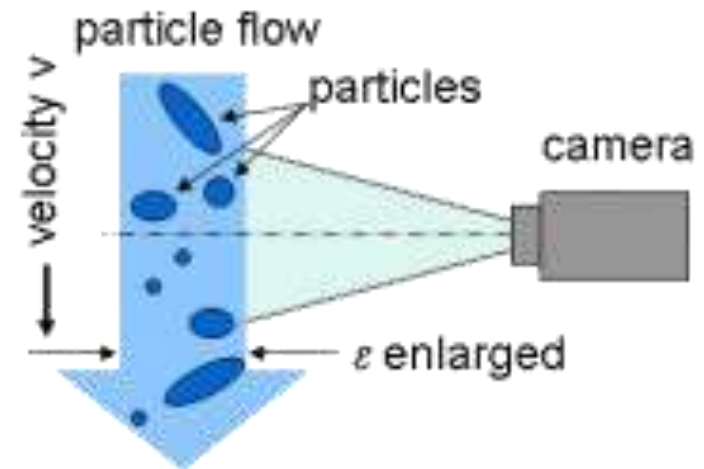
- Low resolution, small number of ascertainable classes
- Limited sample amount
- High operation costs (labor, replacement)
- Hard to confirm correct operation
- Cannot see change in size of some particles (e.g., rods)
- No shape analysis possible

# Dynamic Image Analysis (DIA)

- **Particles flow through the measurement volume of the instrument and the field of view of the camera.**
- **Particles images are captured during movement, no other moving parts necessary.**
- **Capturing of many particle images in a short time interval**
- **Particles are projected in random orientation (3D)**

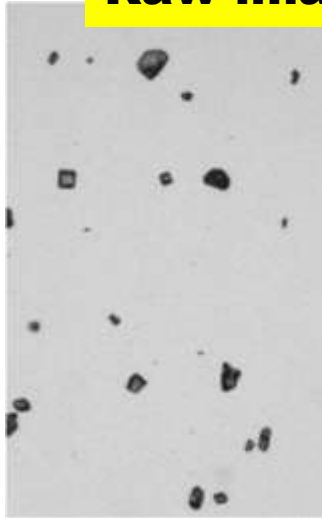


## CAMSIZER



# Data analysis

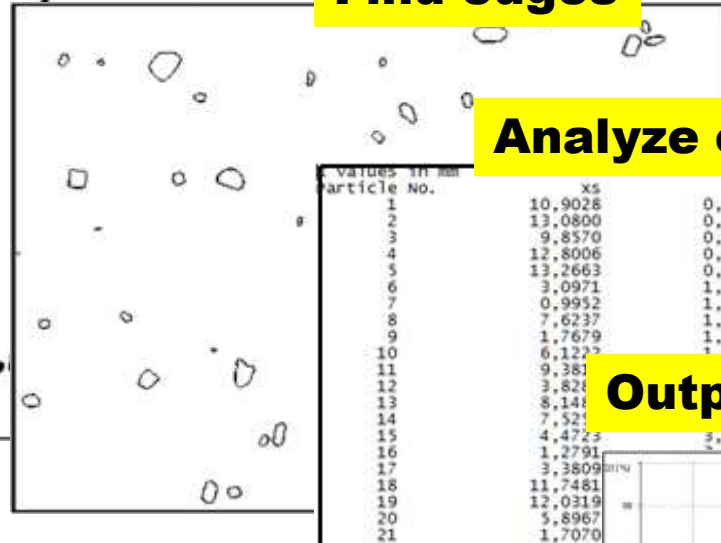
**Raw image**



**Binarize**



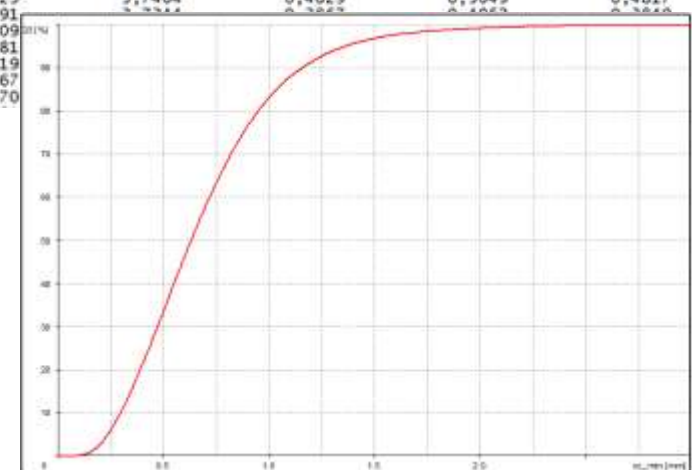
**Find edges**



**Analyze each particle**

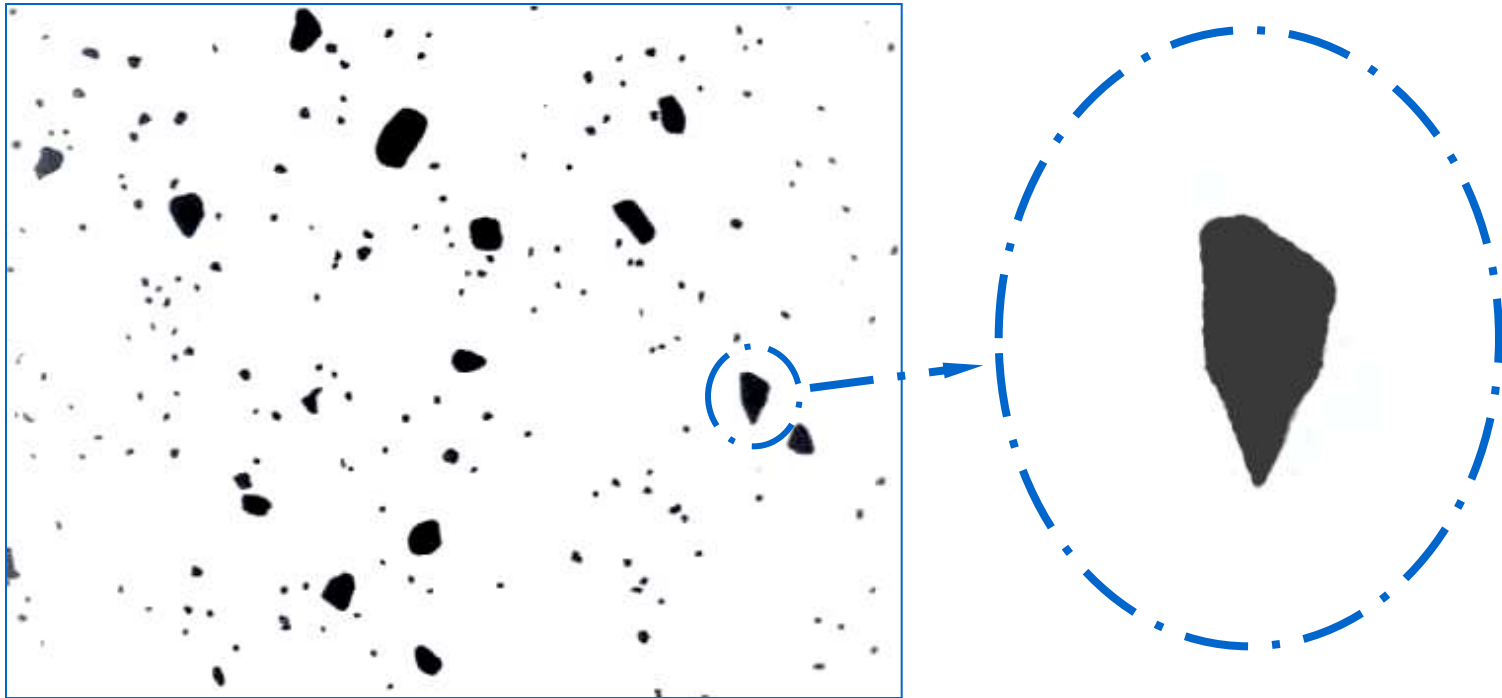
Particle No.	xs	ys	x_area	xFe	xMa
1	10.9028	0.3489	0.1219	0.1269	0.1186
2	13.0800	0.4677	0.2176	0.2234	0.2156
3	9.8570	0.6081	0.4872	0.5260	0.4746
4	12.8006	0.8691	0.3937	0.4154	0.3894
5	13.2663	0.7529	0.2767	0.3113	0.2720
6	3.0971	1.2902	0.5874	0.6104	0.5833
7	0.9952	1.1762	0.2226	0.2342	0.2194
8	7.6237	1.2215	0.1609	0.1668	0.1594
9	1.7679	1.2251	0.1242	0.1237	0.1238
10	6.1223	1.6743	0.3170	0.3363	0.3130
11	9.381				
12	3.821				
13	8.141				
14	7.521				
15	4.4723				
16	1.2791				
17	3.3809				
18	11.7481				
19	12.0319				
20	5.8967				
21	1.7070				

**Output distribution**



# What is the size?

Different measurement systems provide different results.





# Many size measures

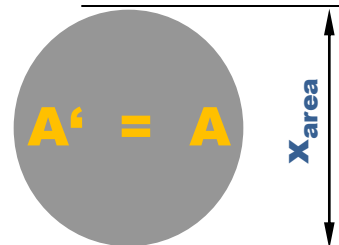
$X_{c\ min}$

“width”



$X_{area}$

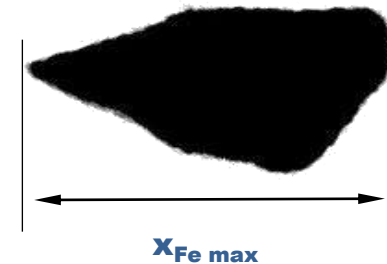
“diameter over  
projection  
surface”



**Width is best  
suited for  
comparison  
with sieves !**

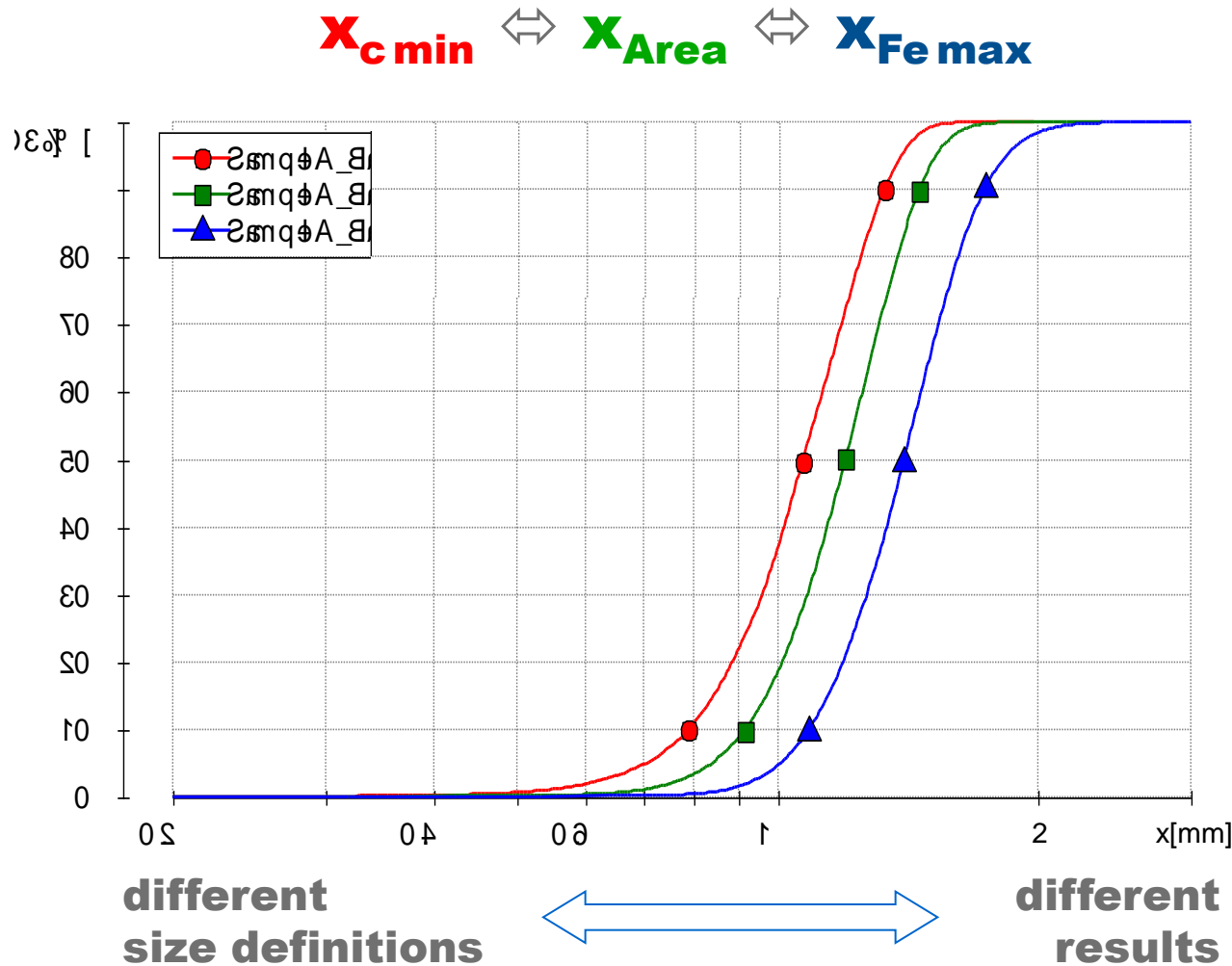
$X_{Fe\ max}$

“length”

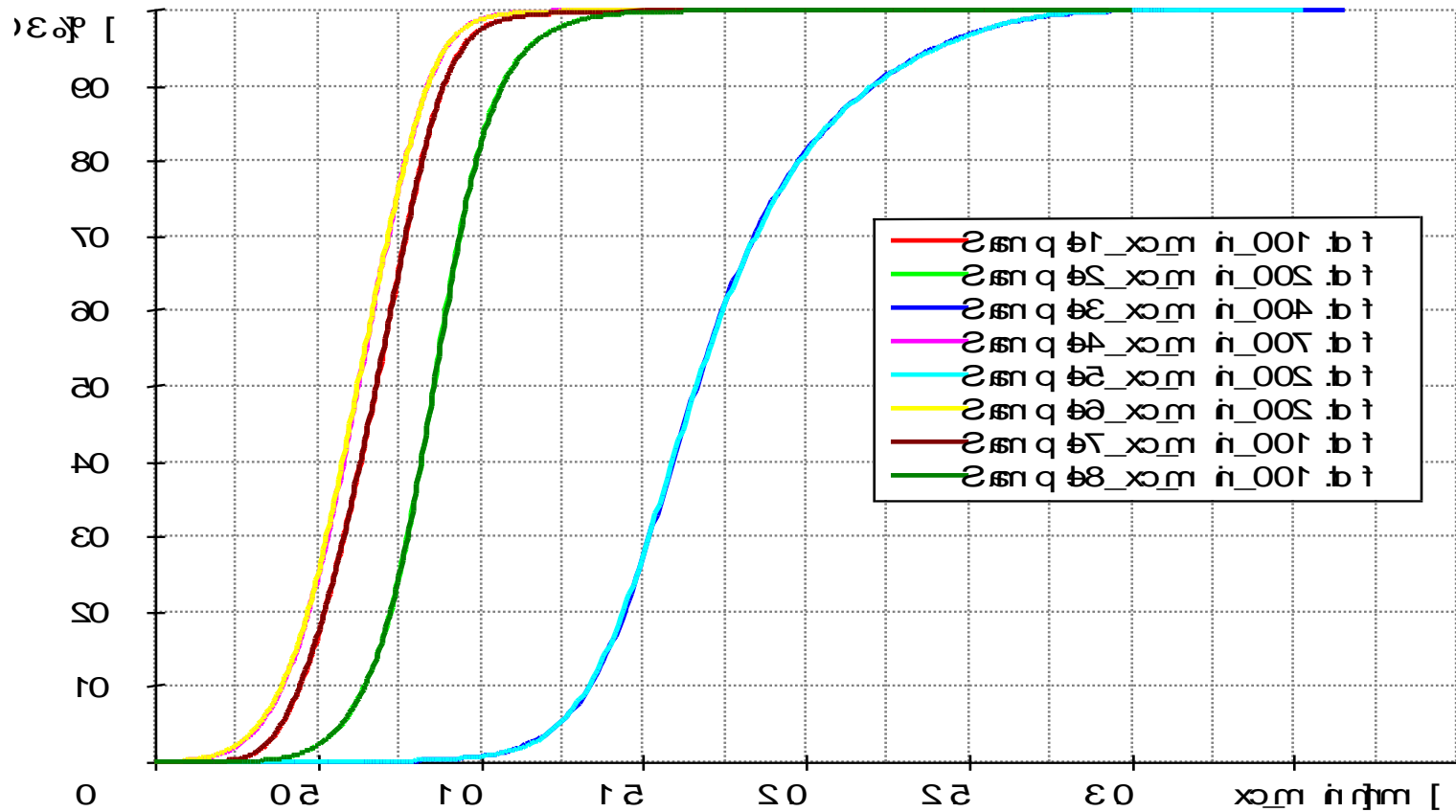


**Shape  
parameters  
can be  
calculated!**

# Comparison of size definitions



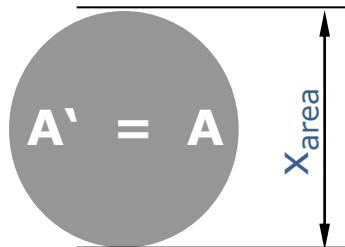
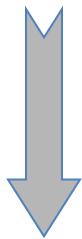
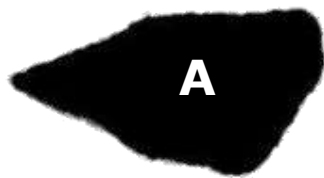
# Image analysis reproducibility



**Samples 1-8, the following samples  
show identical results .**

**1=7, 3=5, 2=8, 4=6**

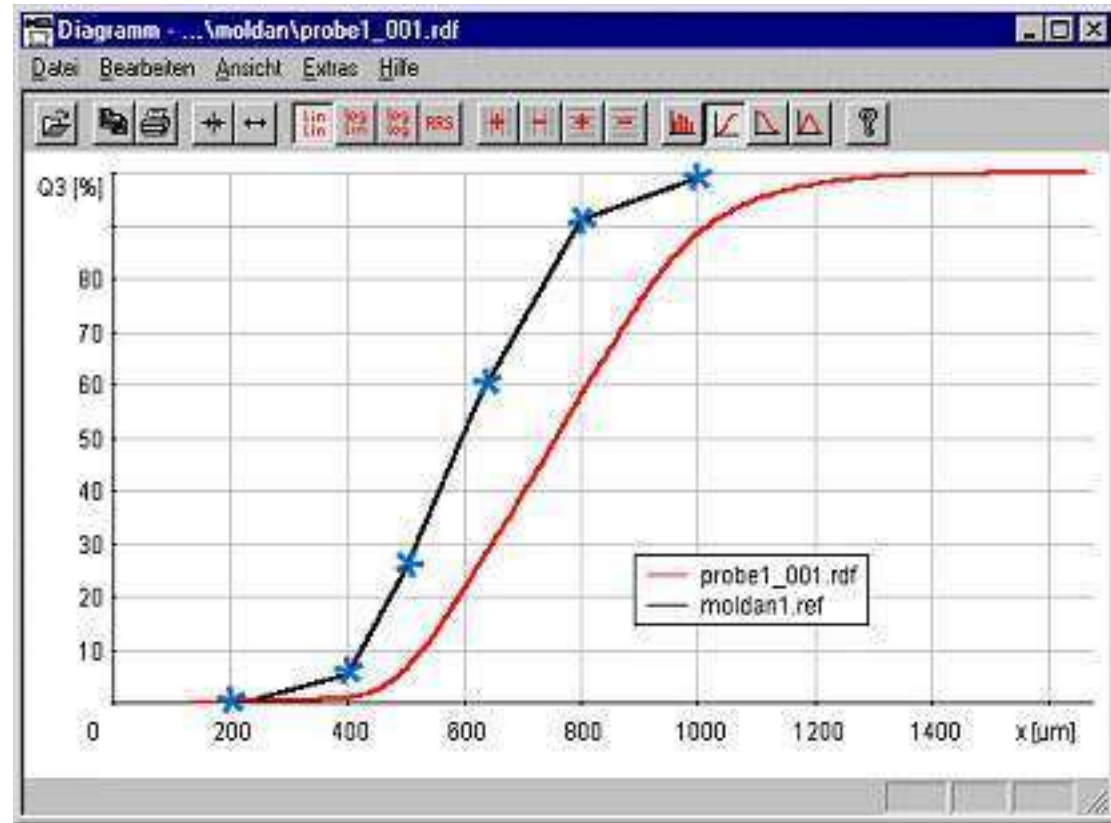
# Area measurement ↔ sieving



$x_{area}$

$x_{area}$

"diameter  
via projection surface"

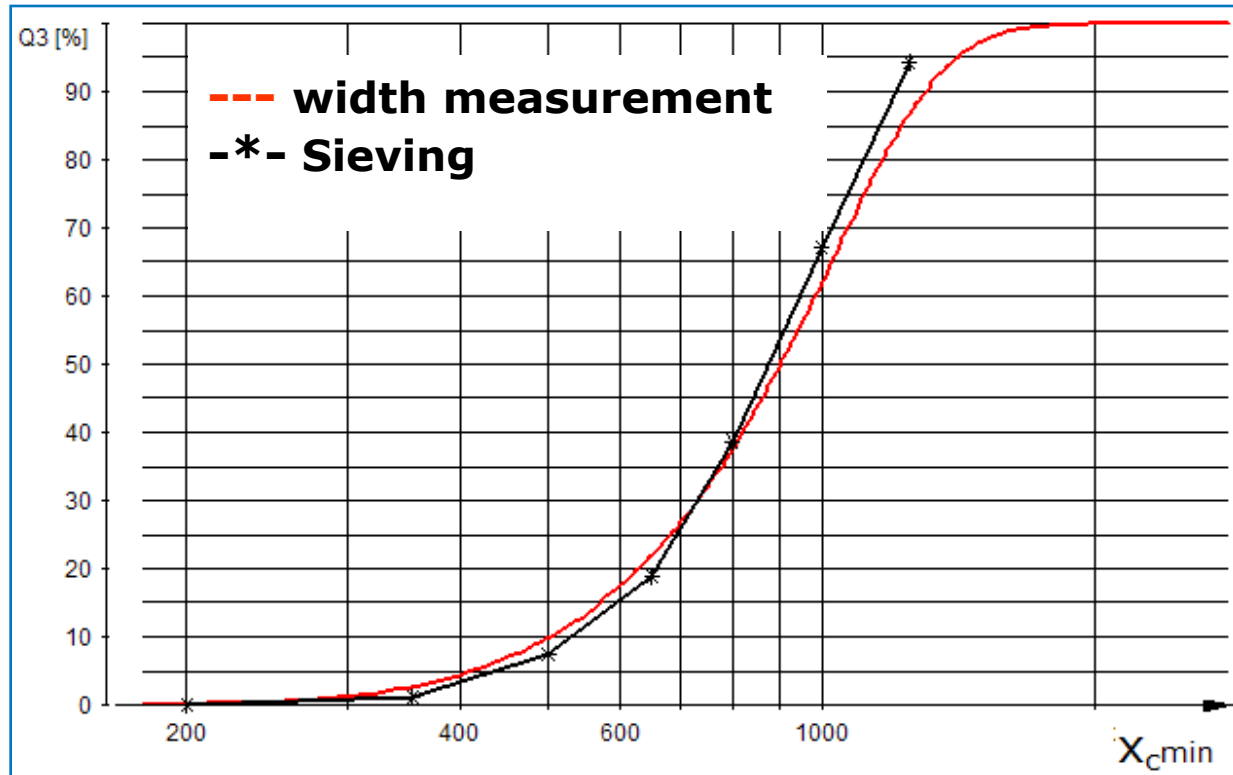
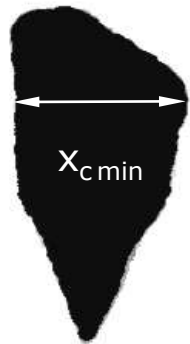


**comparison**

CAMSIZER-measurement  $x_{area}$  (**red**)  
and sieving \* (**blue**)

# Measuring of width ↔ sieving

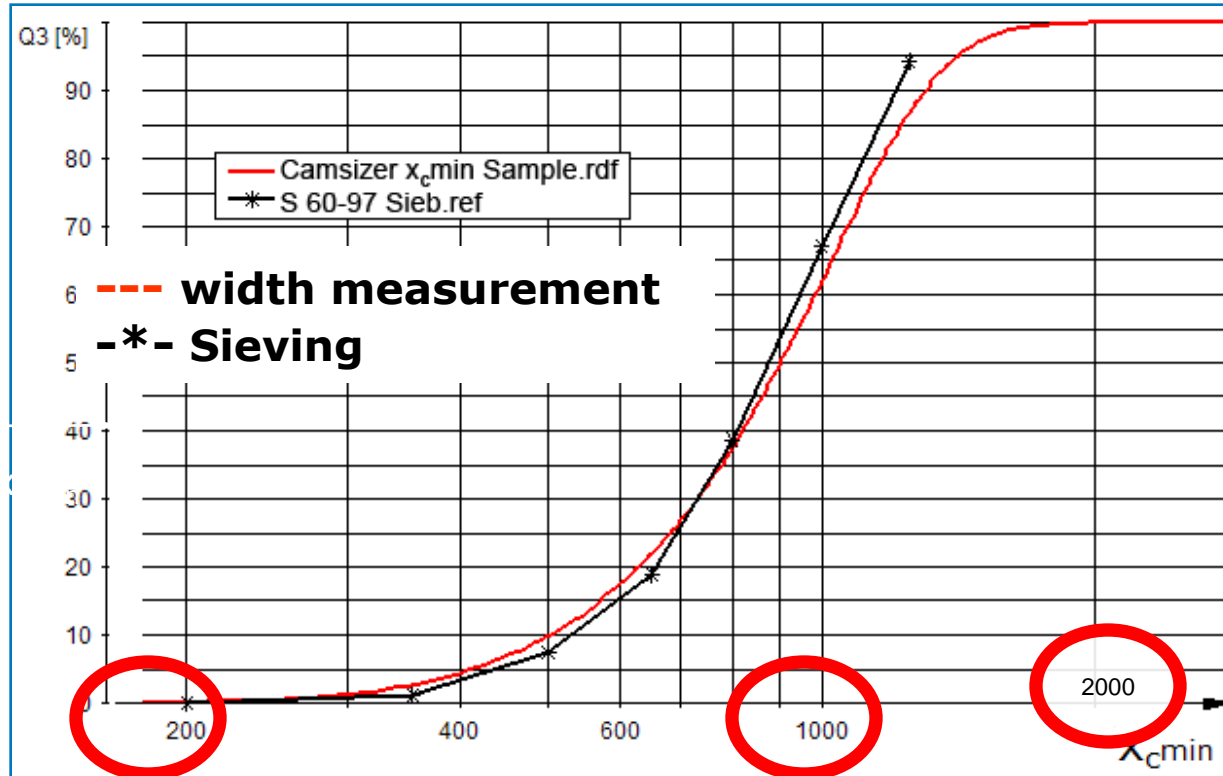
$x_{cmin}$   
"width"



**comparison**

CAMSIZER-measurement  $x_{cmin}$  (**red**)  
and sieving \* (**black**)

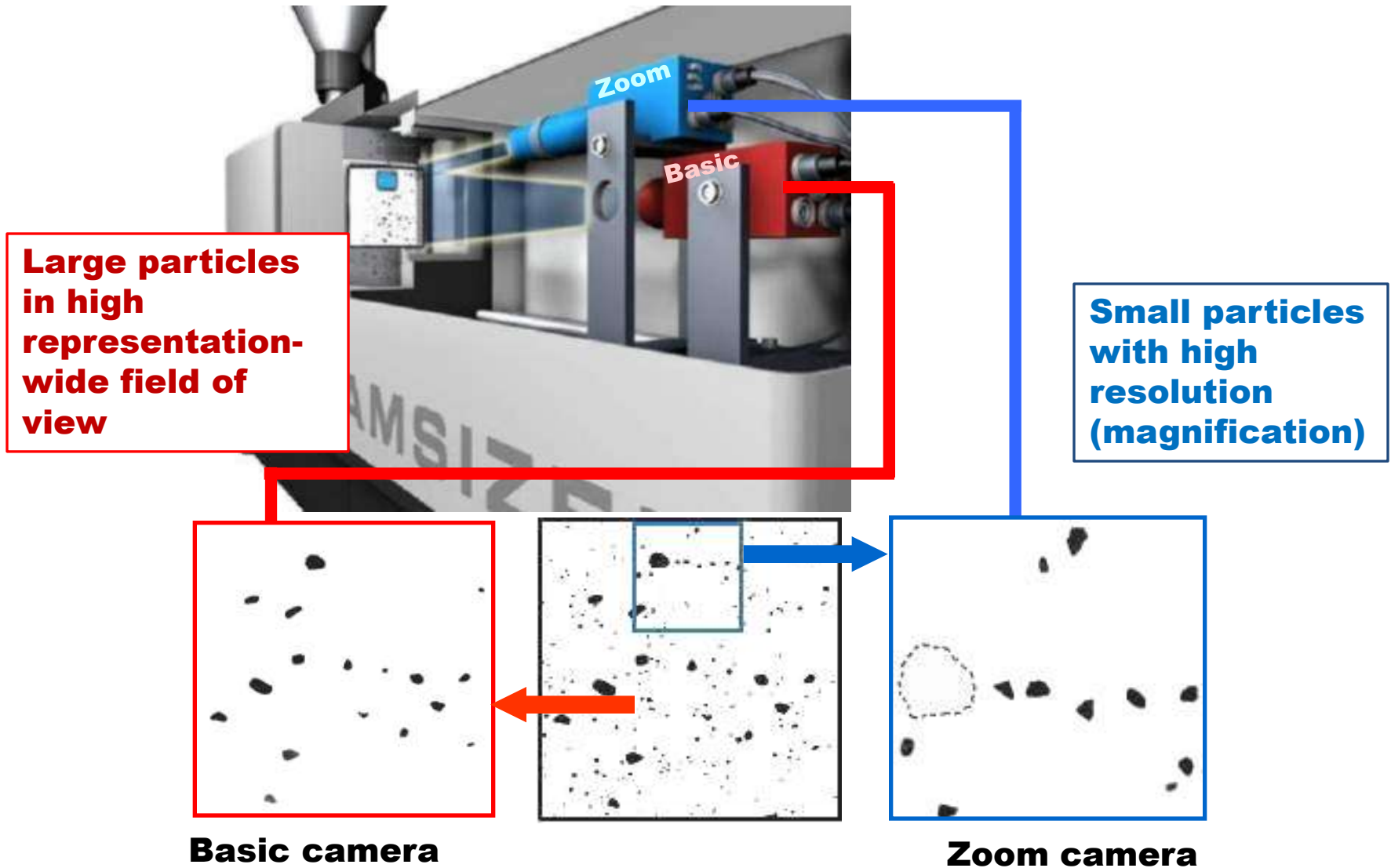
# Size range



Range is 200 to 2000 microns ... (factor 10)

How to cover a wider range or different size products? (factor 1500)

# 2 Camera system for size range



# Calibration



**Master sieve stack  
(that wears with use)**



**Calibration beads**



**Calibration Reticle**

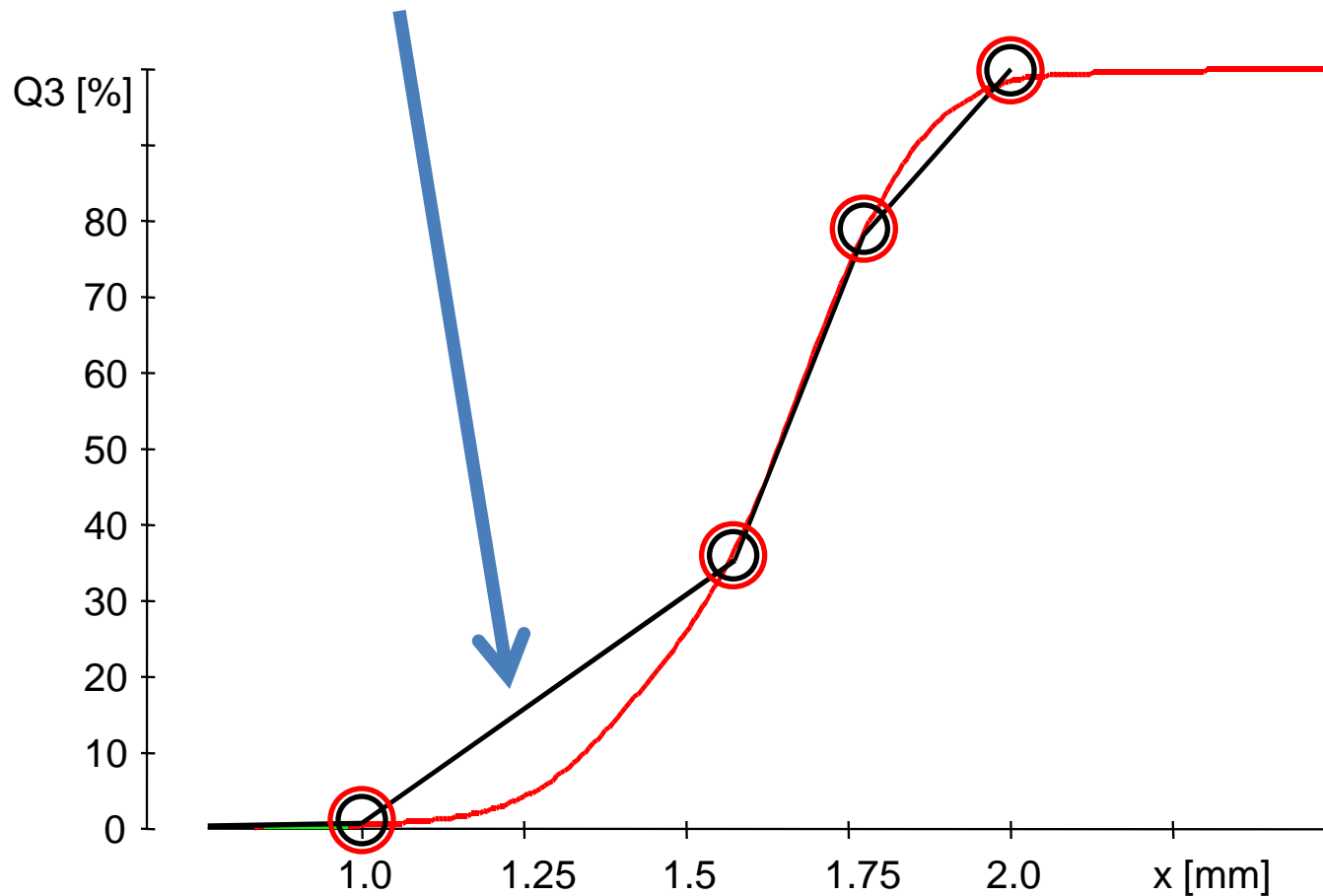


- Traceable to an international standard
- Covers the whole measurement range
- Instrument to instrument agreement
- Does not wear

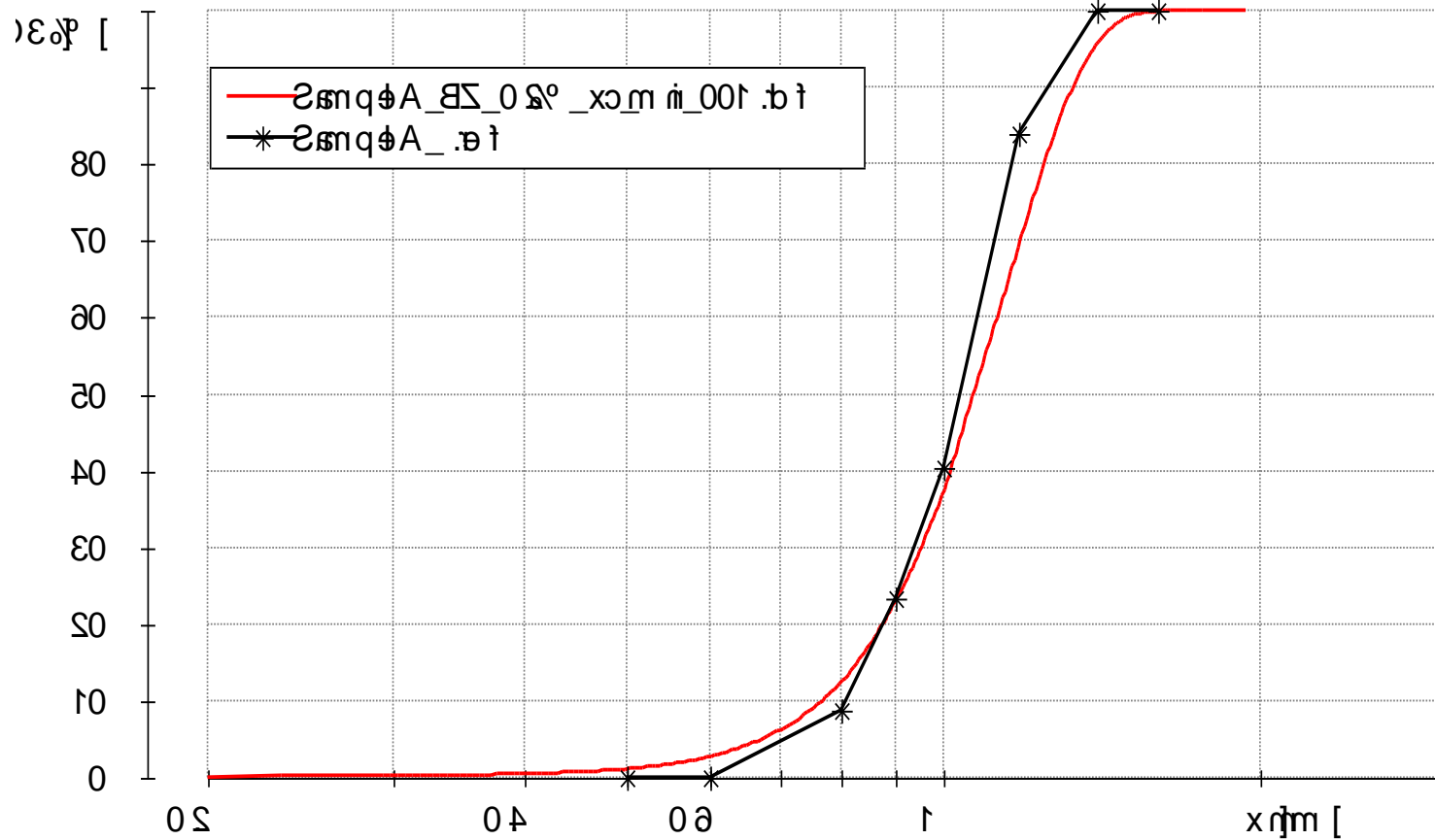


# Resolution and fitting

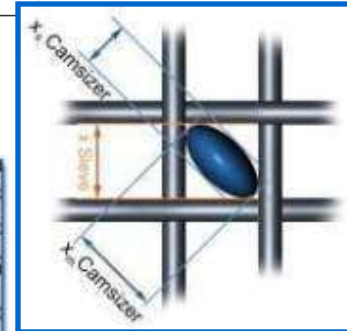
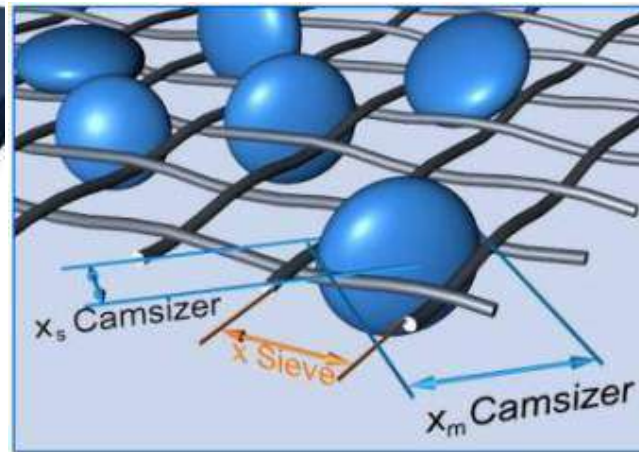
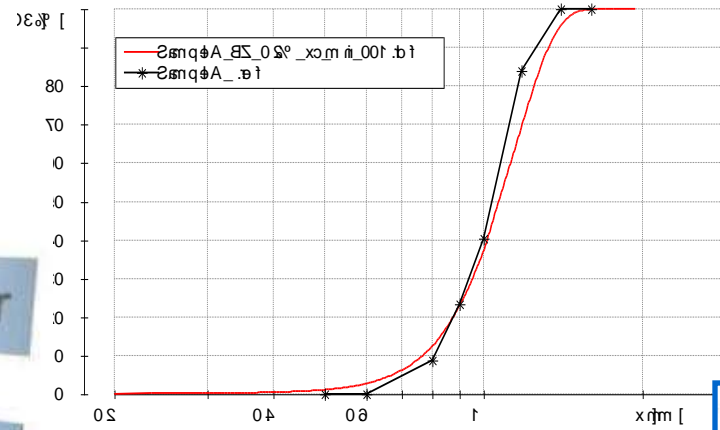
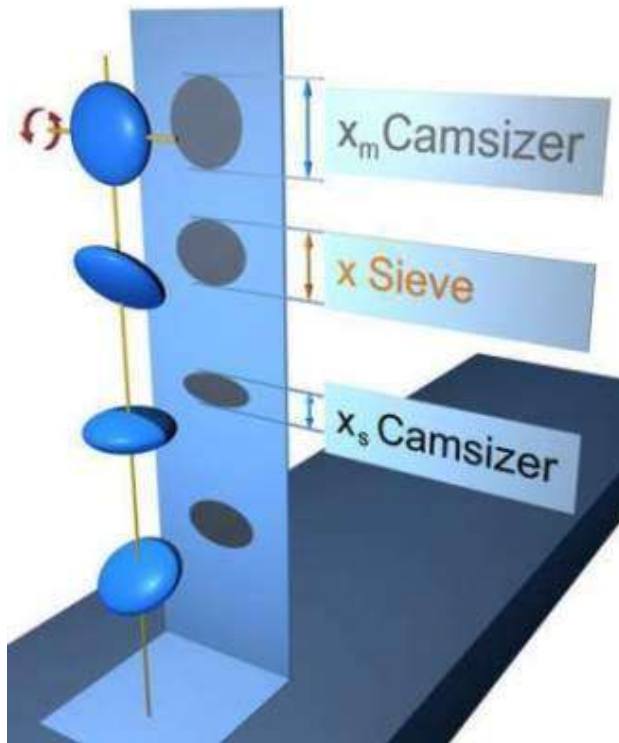
This is due to poor resolution of sieves.



# Lenticular particles

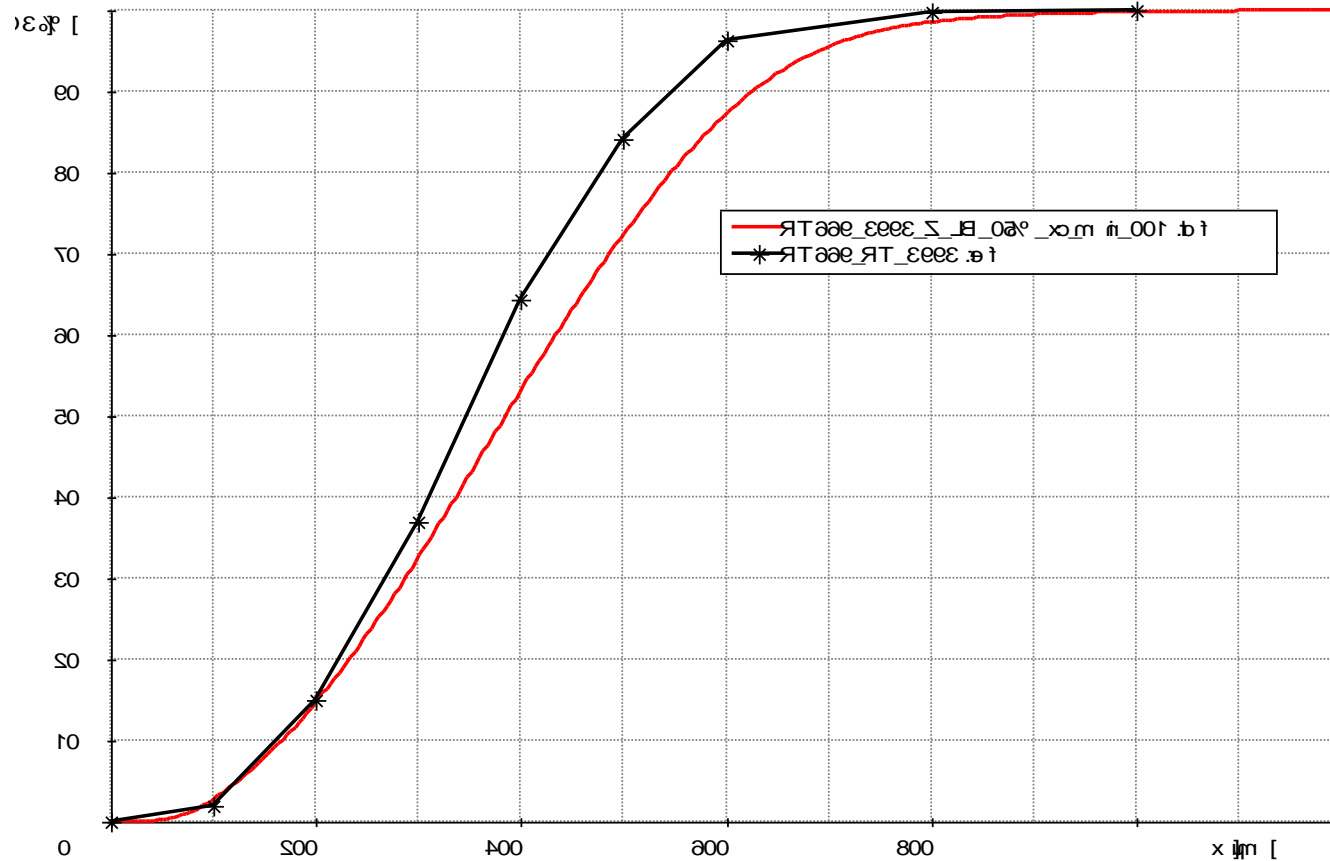


# Lenticular particles

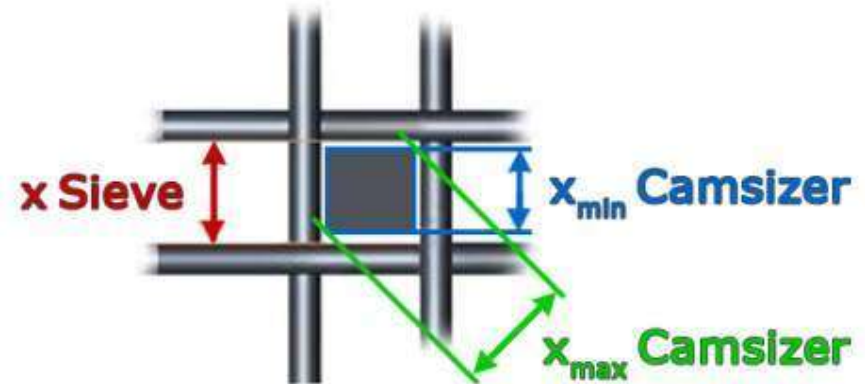
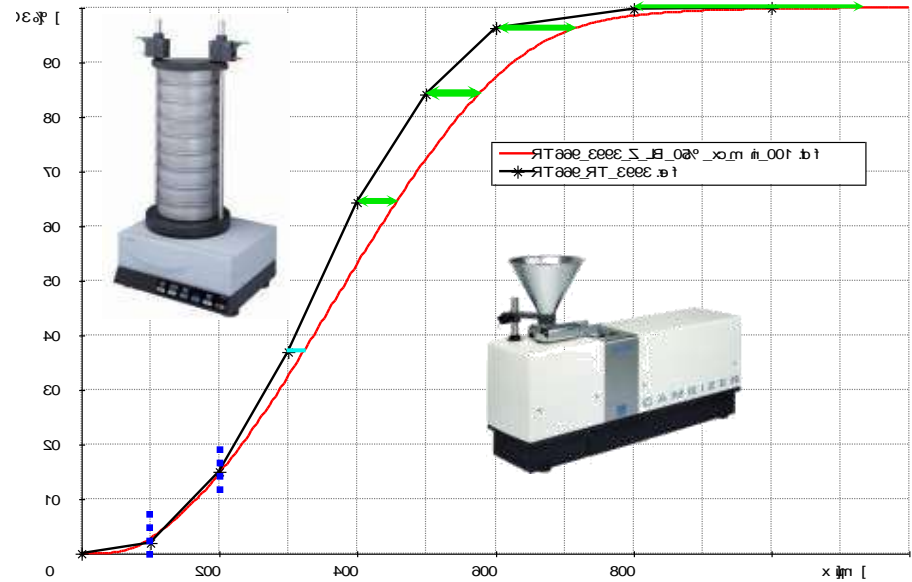
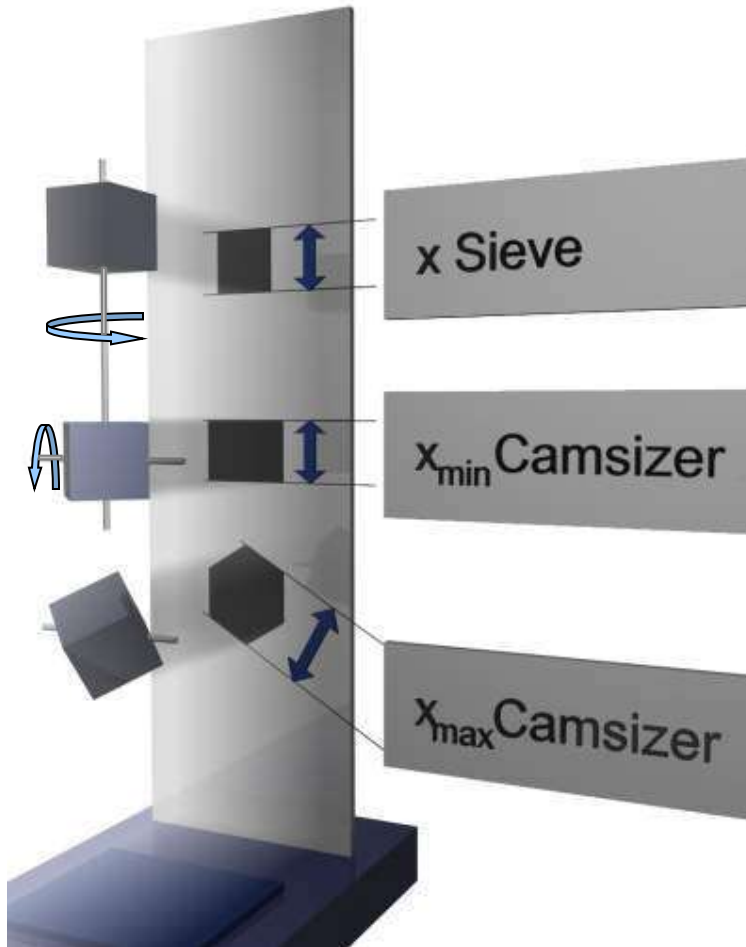


# Angular particles

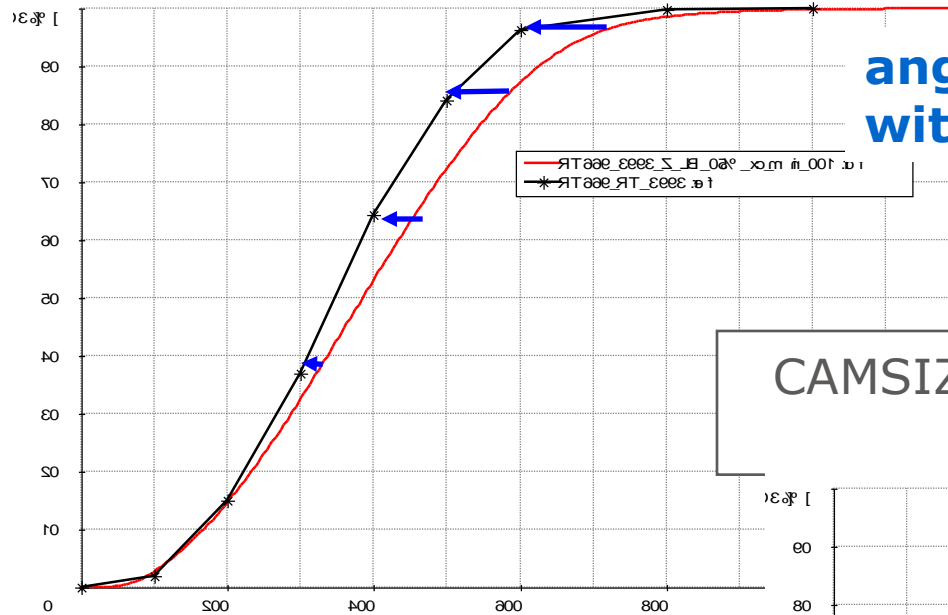
(coal, sand, sugar)



# Cubes / angular particles

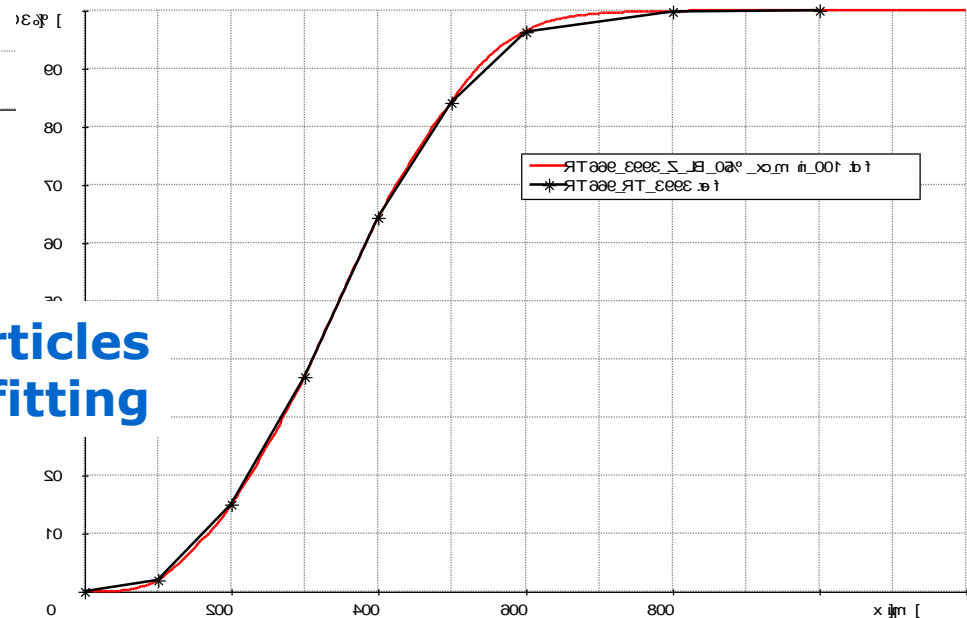


# Fitting ... the final adjustment

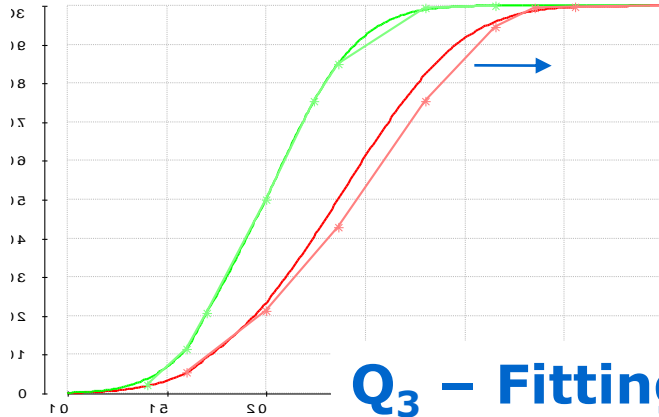


CAMSIZER-measurement  $x_{c \min}$  (red)  
sieve analysis (black)

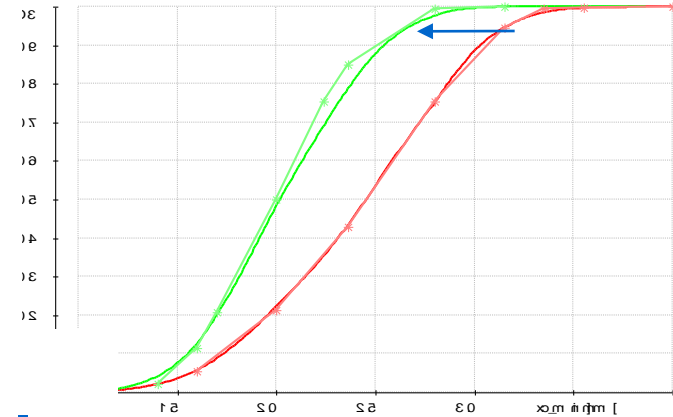
angular particles  
with  $Q_3$ -fitting



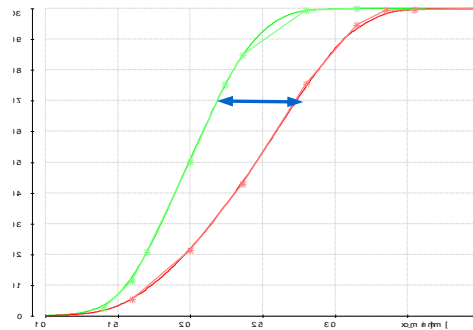
# Limits of $Q_3$ fitting



**$Q_3$  – Fitting**  
**Cannot fit in general.**  
**(all sizes)**



## Elementary – fitting



Create a fitting file

Fitting method:

Data of one sieve class:

Consider raw data files (max: 10):

Melox\_1-35mm\_1%\_B224-235\_1c\_min

Read Remove 1 files

Lower limit (mm): 2.2400

Upper limit (mm): 2.3600 Update

Attention!

The sieve class has to be as small as possible.

Data of entire distribution:

Consider raw data files (max: 10):

Melox\_1-35mm\_1%\_1c\_min\_001.rbf

Read Remove 1 files

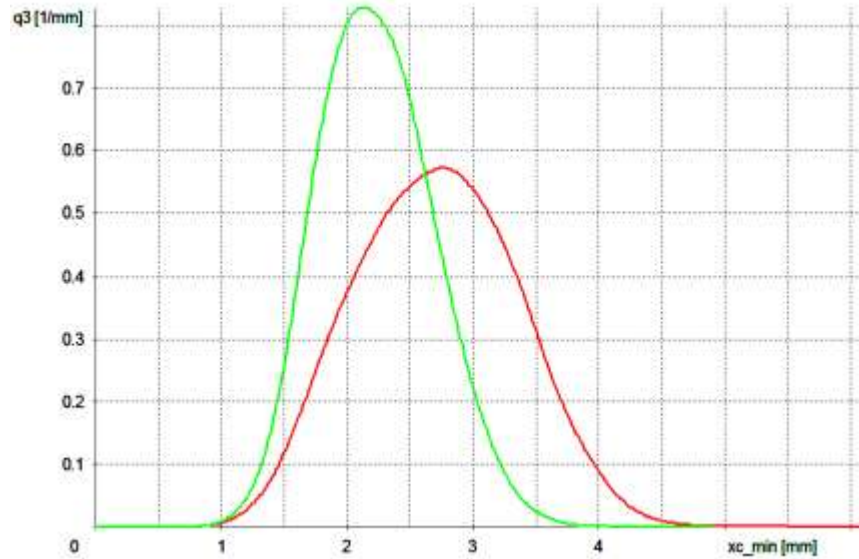
Reference files (sieve): (max: 10):

Melox\_1-35mm.rbf

Read Remove 1 files

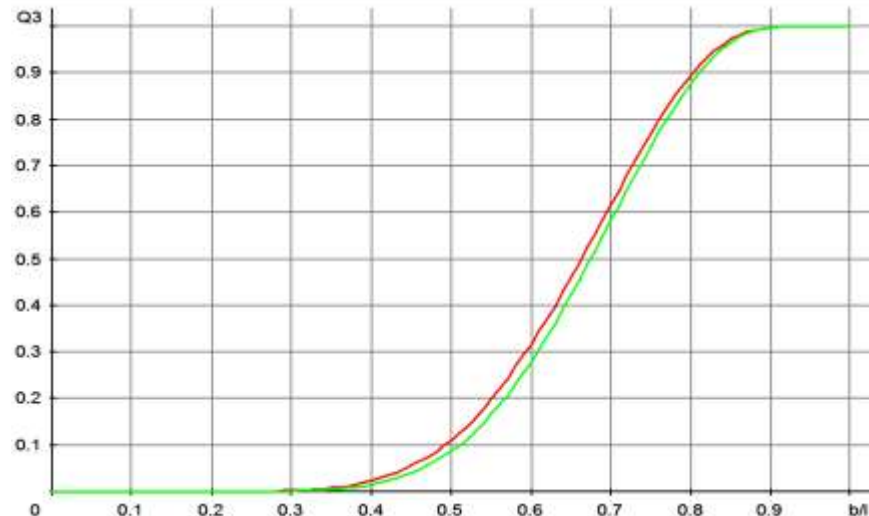
OK Cancel Save

# Elementary fitting



**Two samples  
with different  
width of  
distribution  
but ...**

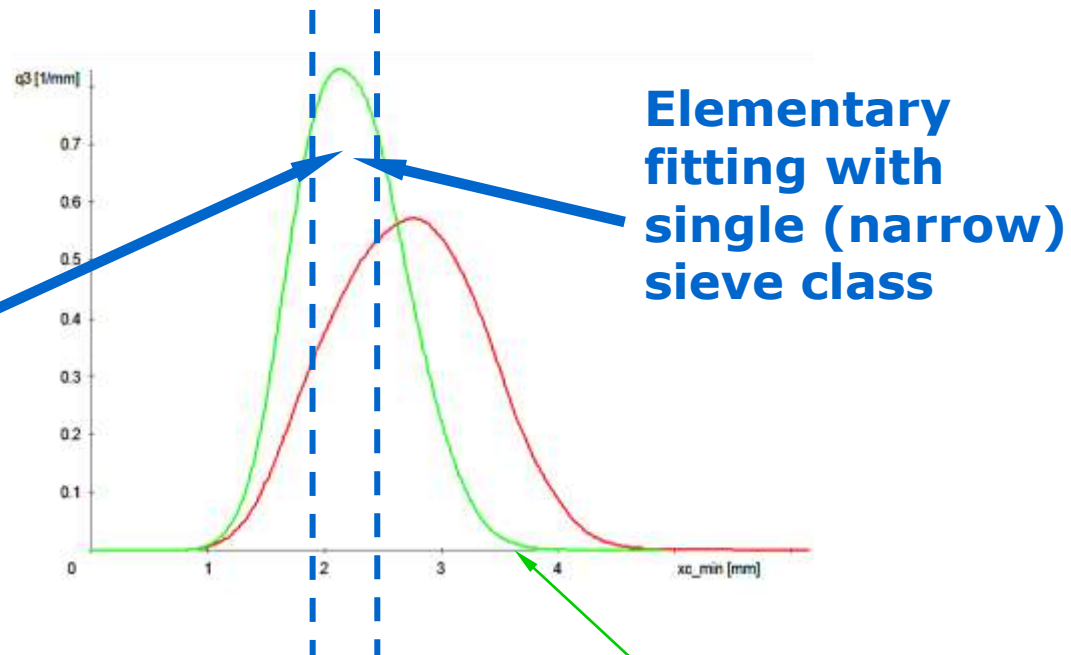
**... with  
similar shape.  
(= same  
product type)**





# Elementary fitting

Digital imaging  $\Leftrightarrow$  sieving

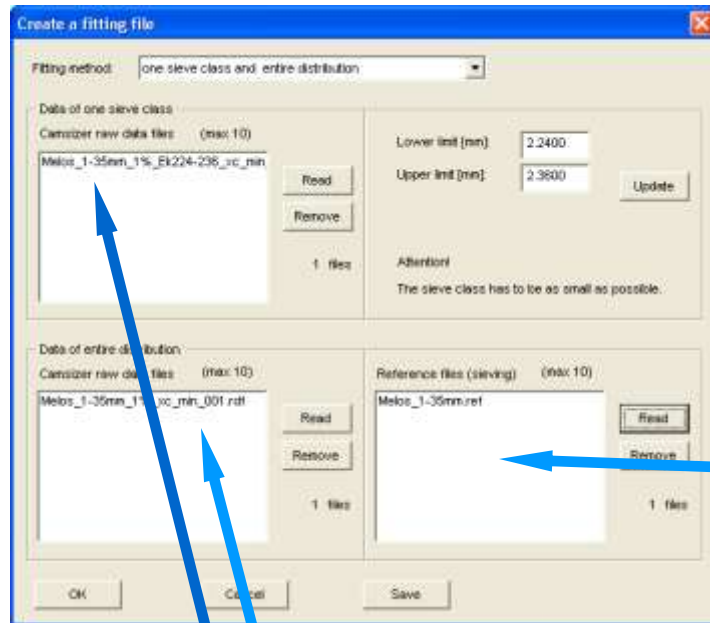


**Single class (element):**  
Taken from the sieve stack  
and measured in CAMSIZER

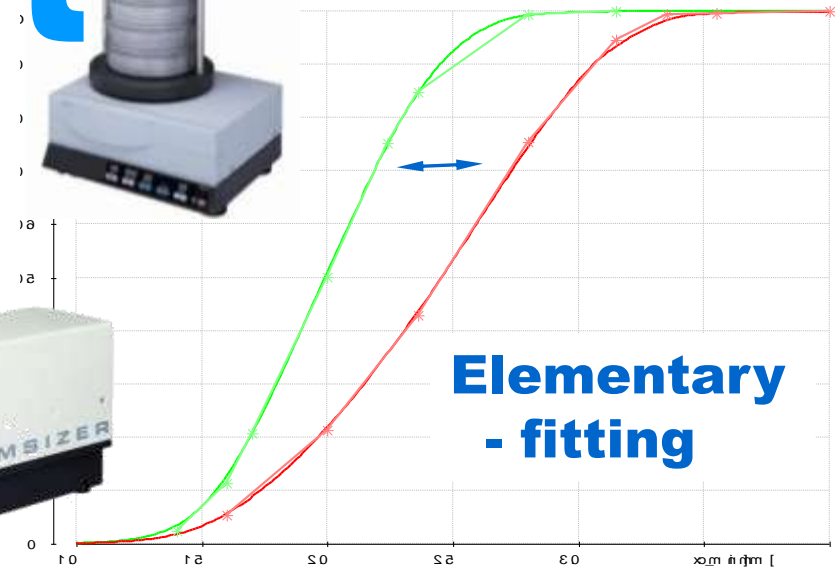
**For the CAMSIZER  
elementary fitting  
use the more narrow sample**



# Elementary fitting



Elementary fitting with **single (narrow) sieve class and entire distribution**

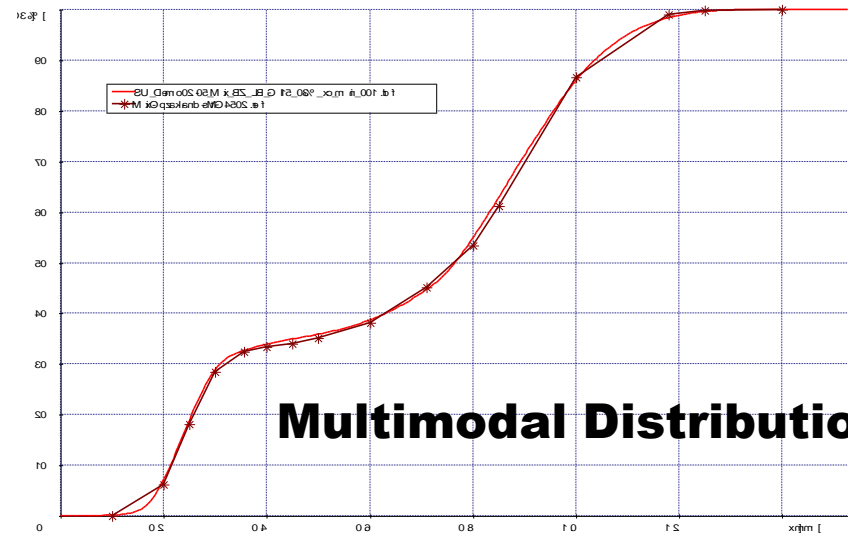
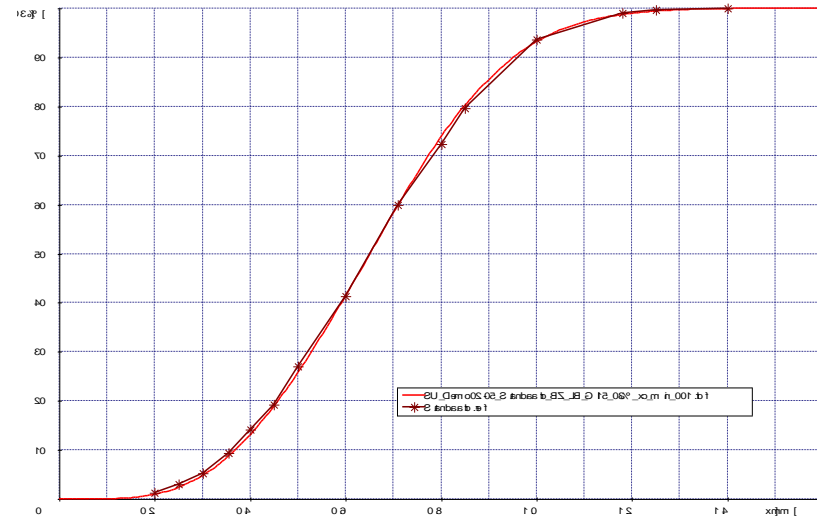


**Elementary - fitting**

# Elementary fitting results

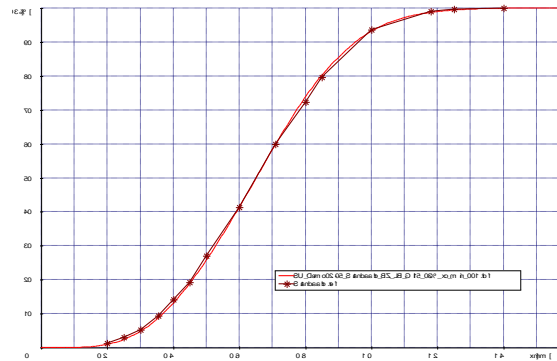
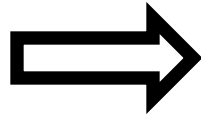
## Elementary Fitting:

- For samples with similar shape
- Fitting of different width of distribution possible (even multimodal distributions)
- Applications: sand, sugar, fertilizer, minerals, plastics, foodstuffs...
- Samples with varying particle shape, e. g. abrasives will need different fitting files



**Multimodal Distributions**

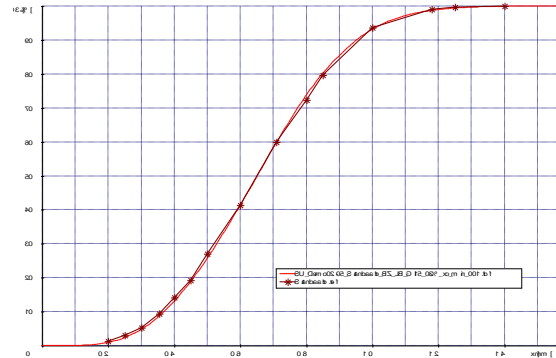
# Conclusions



**The Camsizer can be used in place of sieves to provide fast, easy data. It also provides shaped data.**

**Historical sieve data can be matched through an elementary fitting process. This requires one (good) sieving and two Camsizer measurements.**

# Image analysis advantages



<b>Sieve</b>	<b>CAMSIZER</b>
<b>Low resolution</b>	<b>High resolution</b>
<b>Limited sample amount</b>	<b>Flexible sample amount</b>
<b>No shape information</b>	<b>Shape information included</b>
<b>High labor costs</b>	<b>Low labor costs</b>
<b>Hard to check accuracy</b>	<b>Easy accuracy check</b>
<b>Cannot see doublets</b>	<b>Easy to analyze doublets and other complex shapes</b>

# Questions?

**Ask a question at [labinfo@horiba.com](mailto:labinfo@horiba.com)**

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**Thank-you**

Thank you very much for your attention.

# Thank you

Omoshiro-okashiku  
Joy and Fun

감사합니다

**Cảm ơn**

ありがとうございました

**Dziękuję**

धन्यवाद

**Grazie**

**Merci**

谢谢

நன்ற

ขอบขอบคุณ

**Obrigado**

Σας ευχαριστούμε

شُكْرًا

**Tack ska ni ha**

Большое спасибо

**Danke**

**Gracias**

おもしろおかしく  
ありがとうございます

眞峰

